

MONTE CARLO METHODS FOR ELECTRON TRANSPORT

**Mark J. Kushner
University of Illinois
Department of Electrical and Computer Engineering
1406 W. Green St.
Urbana, IL 61801 USA
217-244-5137 mjk@uiuc.edu <http://uigelz.ece.uiuc.edu>**

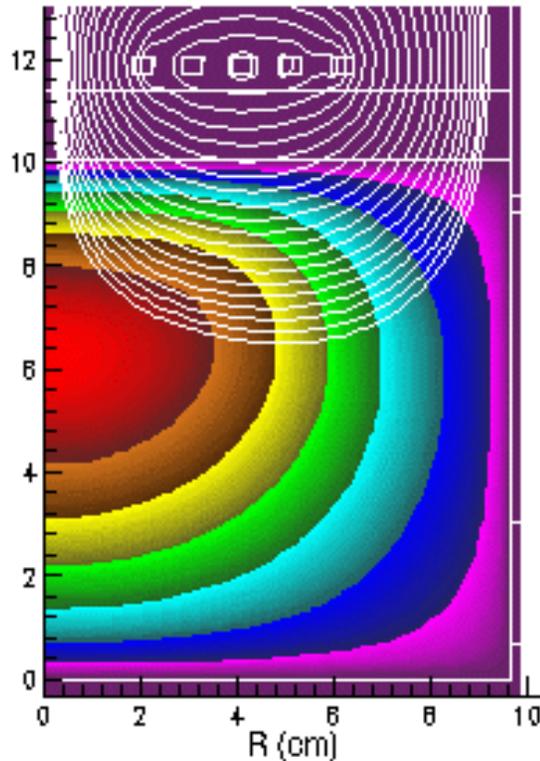
May 2002

MONTE CARLO METHODS FOR ELECTRON TRANSPORT

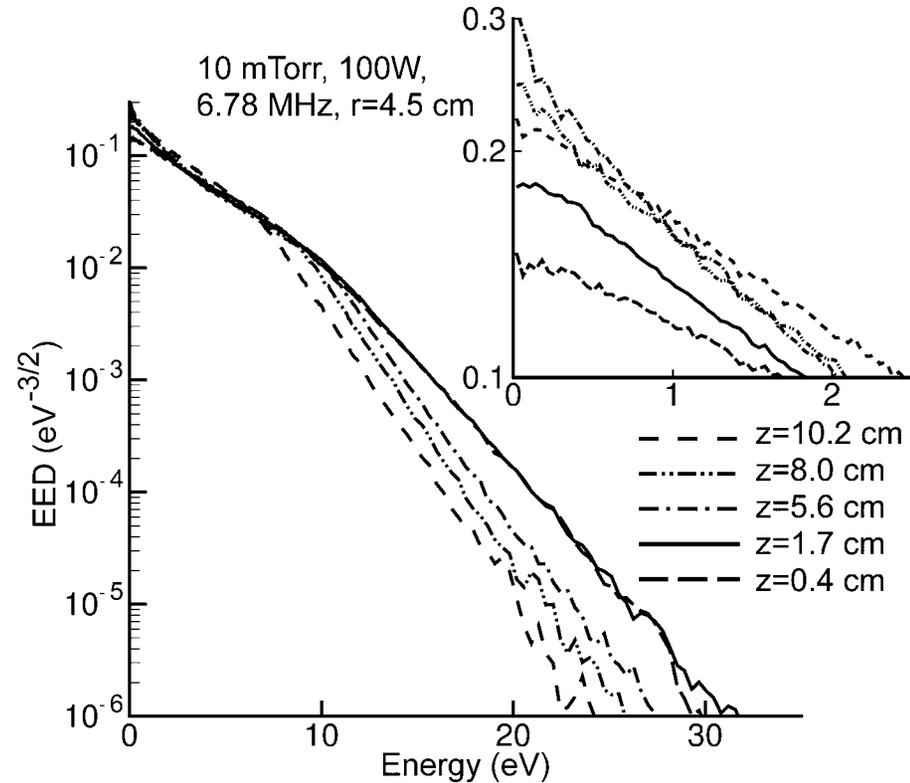
- **The Monte Carlo (MC) method was developed during WWII for analysis of neutron moderation and transport.**
- **MC methods enable direct simulation of complex physical phenomena which may not be amenable to conventional PDE analysis.**
- **The method relies upon knowledge of probability functions for the phenomena of interest to statistically (randomly) select occurrences of events whose ensemble average is “the answer”.**
- **These methods are extensively used in simulating electron transport do obtain, for example, electron energy distributions.**

EXAMPLE: ELECTRON ENERGY DISTRIBUTION IN ICP

- Inductively Coupled Plasma: Ar, 10 mTorr, 6.78 MHz



- Electric field (overlay) and ion density (max = $1.7 \times 10^{11} \text{ cm}^{-3}$)



- EED at $r=4.5 \text{ cm}$ vs Distance from Window

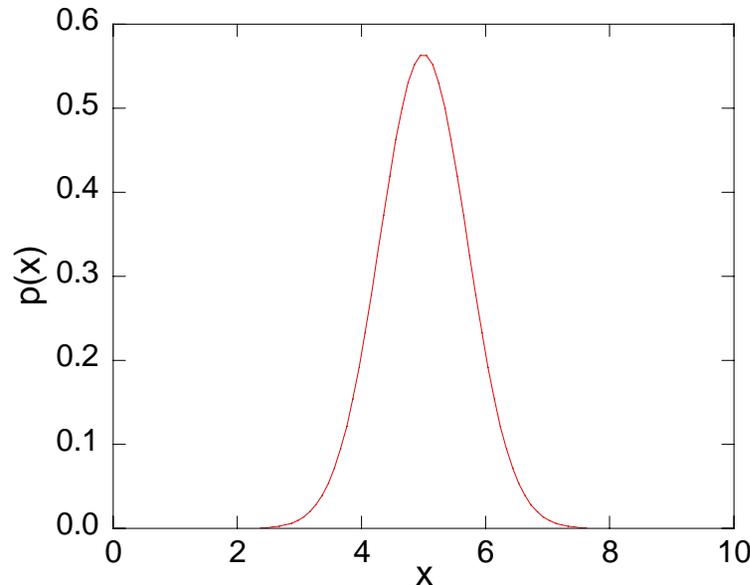
University of Illinois
Optical and Discharge Physics

MONTE CARLO METHOD REFERENCES

- J. P. Boeuf and E. Marode, J. Phys. D 15, 2169 (1982)
- G. L. Braglia, Physica 92C, 91 (1977)
- S. R. Hunter, Aust. J. Phys. 30, 83 (1977)
- S. Lin and J. Bardsley, J. Chem. Phys 66, 435 (1977)
- S. Longo, Plasma Source Science Technol. 9, 468 (2000)
- J. Lucas, Int. J. Electronics 32, 393 (1972)
- J. Lucas and H. T. Saelee, J. Phys. D 8, 640 (1975)
- K. Nanbu, Phys. Rev E 55, 4642 (1997)
- M. Yousfi, A. Hennad and A. Alkaa, Phys Rev E 49, 3264 (1994)
- **Computational Science and Engineering Project**
<http://csep1.phy.ornl.gov>, <http://csep1.phy.ornl.gov/CSEP/MC/MC.html>

BASICS OF THE MONTE CARLO METHOD: $p(x)$

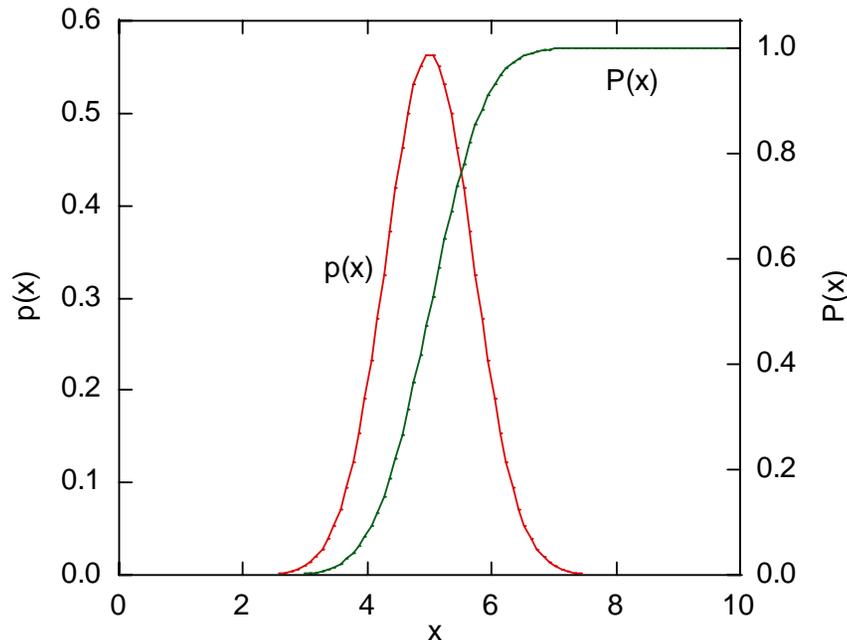
- A physical phenomenon has a known probability distribution function $p(x)$ which, for example, gives the probability of an event occurring at position x .



$$\int_0^{\infty} p(x) dx = 1$$

BASICS OF THE MONTE CARLO METHOD: P(x)

- The cumulative probability distribution function $P(x)$ is the likelihood that an event has occurred prior to x .



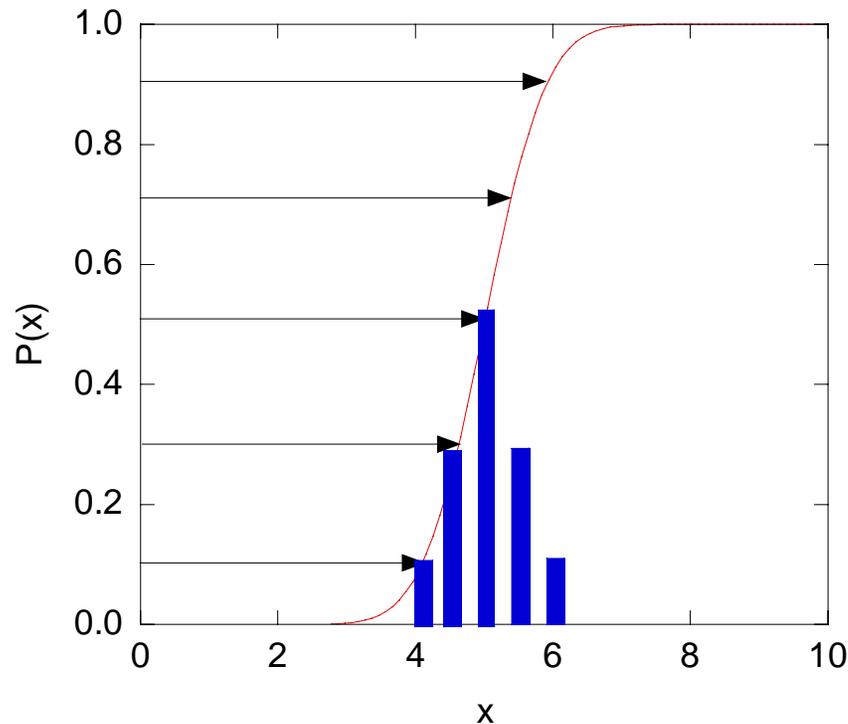
$$P(x) = \int_0^x p(x') dx'$$

$$P(0) = 0, \quad P(\infty) = 1$$

- Since $p(x)$ is always positive, there is a 1-to-1 mapping of $r=[0,1]$ onto $P(x = 0 \rightarrow x = \infty)$.

RANDOM USE OF $P(x)$ TO REGENERATE $p(x)$

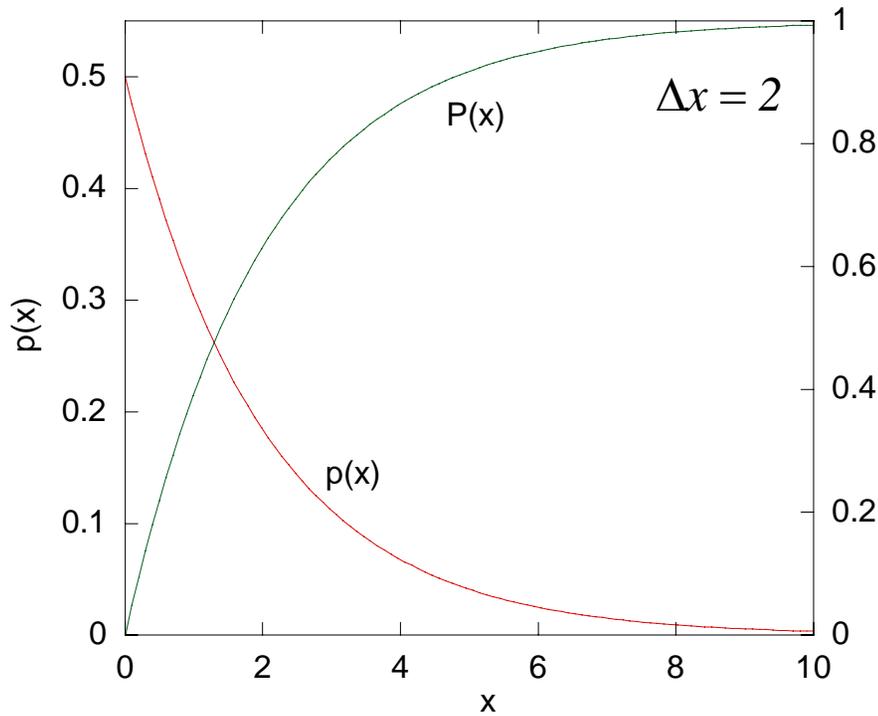
- By randomly choosing “product values” of $P(x)$ (distributed $[0,1]$) and binning the occurrences of the argument x , we reproduce $p(x)$.



- The function which, given a random number $r=[0,1]$, provides a randomly selected value of x is:

$$x = P^{-1}(r)$$

EXAMPLE: RANDOM P(x) TO REGENERATE p(x)



$$p(x) = \frac{1}{\Delta x} \exp\left(-\frac{x}{\Delta x}\right)$$

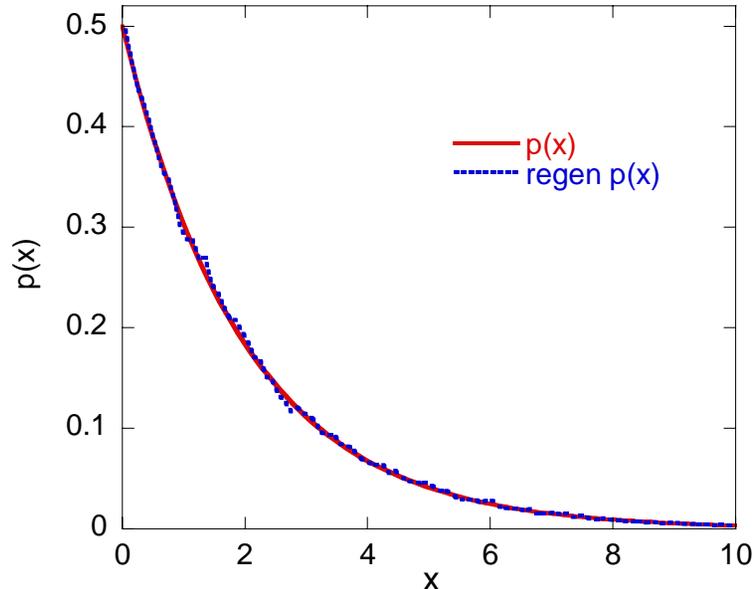
$$P(x) = 1 - \exp\left(-\frac{x}{\Delta x}\right)$$

$$x = P^{-1}(r) = -\Delta x \cdot \ln(1 - r)$$

$$r = [0, 1]$$

- **WARNING!!!** In practical problems, $p(x)$ cannot be analytically integrated for $P(x)$ and/or $P(x)$ cannot be analytically inverted for $P^{-1}(x)$. These operations must be done numerically.

EXAMPLE: RANDOM P(x) TO REGENERATE p(x)

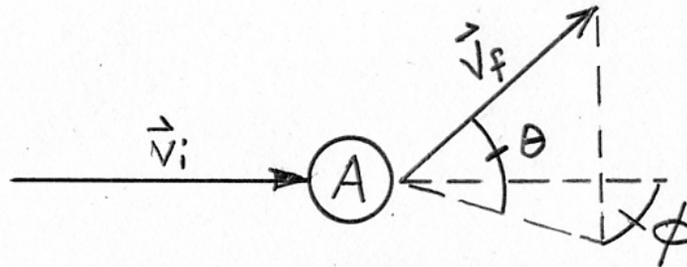


- **p(x) is reproduced within random statistical error ($n^{-1/2}=0.01$).**

```
ibins=100
itrials=10000
deltax=2
xmax=10.
dx=xmax/ibins
ynorm=0.
do i=1,itrials
  r = random(iseed)
  x=-deltax*aolog(1.-r)
  ibin=x/dx
  ynorm=ynorm+dx
  y(ibin)=y(ibin)+1.
end do
do i=1,ibins
  y(i)=y(i)/ynorm
end do
```

ELECTRON SCATTERING

- An electron with energy ε collides with an atom with differential cross section $\sigma(\varepsilon, \theta, \phi)$



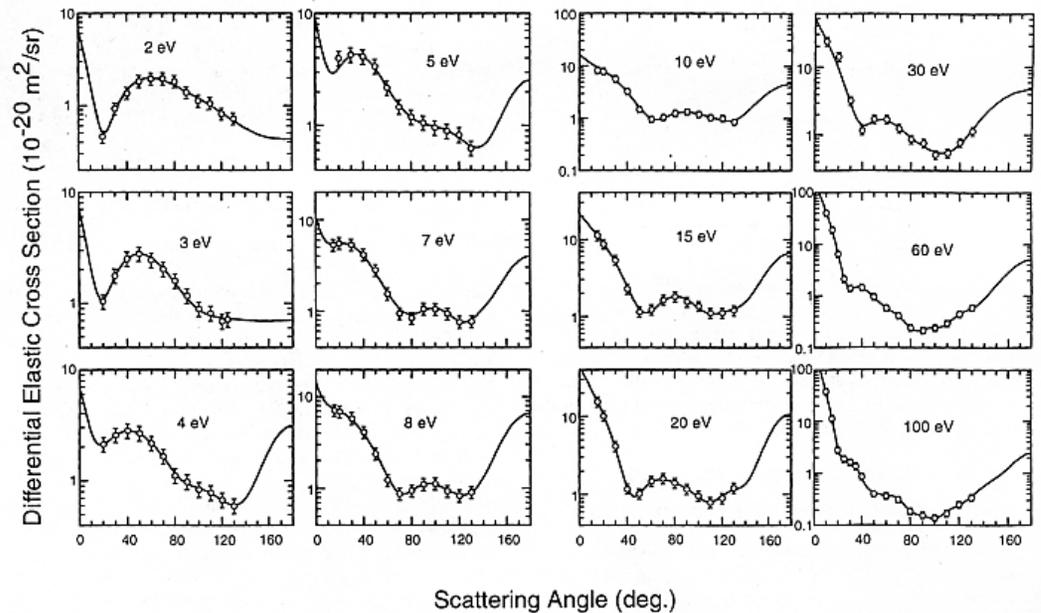
providing the likelihood of scattering into the solid angle centered on (θ, ϕ) .

Note: Typically only the explicit dependence on polar angle θ is considered. Scattering with azimuthal angle ϕ is usually assumed to be uniform.

DIFFERENTIAL SCATTERING

- $\sigma(\varepsilon, \theta)$ for real atoms and molecules can be quite complex (C_2F_6)

Christophorou, J. Chem. Phys. Ref. Data 27, 1, (1998)



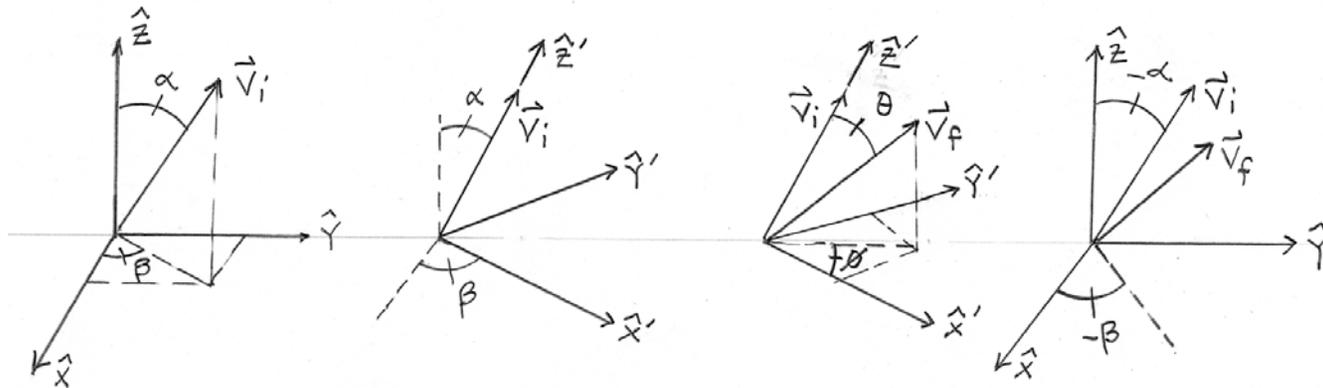
- Accounting for forward scattering at higher energies (> 10s eV) is very important in simulating electron transport.
- Assuming Isotropic scattering in the polar direction yields:

$$\sigma(\theta) = \sigma_o, \quad P(\theta) = \frac{1}{2\sigma_o} \int_0^\theta \sigma_o \sin(\theta') d\theta', \quad \theta = \arccos(2r - 1)$$

University of Illinois
Optical and Discharge Physics

COLLISION DYNAMICS

- To account for the change in velocity of an electron following a collision:



1. Determine Eulerian angles (β, α) of $\vec{v}_{initial}$
2. Rotate frame by (β, α) so z-, x-axes align with $\vec{v}_{initial}$
3. Rotate $\vec{v}_{initial}$ by (θ, ϕ) to yield direction of \vec{v}_{final}
4. Account for change in speed $|\vec{v}_{final}|^2 = |\vec{v}_{initial}|^2 - 2\Delta\varepsilon / m_e$
5. Rotate frame by $(-\alpha, -\beta)$ to original orientation

COLLISION DYNAMICS

- End result is the “scattering matrix” which transforms initial velocity to final velocity:

$$\vec{v}_{final} = \begin{bmatrix} \cos(\beta)\cos(\alpha)\sin(\theta)\cos(\phi) + \cos(\beta)\sin(\alpha)\cos(\theta) - \sin(\beta)\sin(\theta)\sin(\phi) \\ \sin(\beta)\cos(\alpha)\sin(\theta)\cos(\phi) + \sin(\beta)\sin(\alpha)\cos(\theta) - \cos(\beta)\sin(\theta)\sin(\phi) \\ -\sin(\alpha)\sin(\theta)\cos(\phi) + \cos(\alpha)\cos(\theta) \end{bmatrix} \cdot \vec{v}_{initial}$$

EXAMPLE: ELECTRON SWARM

- A swarm of electrons drifts in a uniform electric field in a gas having a constant elastic collision frequency and isotropic collisions. What is the average drift velocity?
- For constant collision frequency ν , the randomly selected time between collisions is:

$$\Delta t = -\frac{1}{\nu} \cdot \text{alog}(1-r)$$

- The change in energy in an elastic collision is

$$\Delta \varepsilon = \left(1 - \frac{2m_e}{M} (1 - \cos(\theta)) \right)$$

EXAMPLE: PROGRAM DRIFT

```
PROGRAM DRIFT
C
C Initialize random number generators. IMPORTANT: Use a different
C sequence of random numbers for different processes
C
DO I=1,3
  CALL INIT_RAN(I)
END DO
C
XMASSE=0.911E-27          ! Electron mass (g)
XMASSN=20.*1.67E-24      ! Atomic mass (g)
C
C select electric field and collision frequency.
C
EFIELD=5.                ! V/cm. Assume in the x-direction
COLF=1.E9                ! 1/s
ACX=EFIELD*1.6E-12/XMASSE ! Acceleration
IELECTRONS=1000         ! Number of electron particles
XEND=20.                 ! Drift distance (cm)
TTOTAL=0.               ! Drift time (s)
VDRIIFT=0.              ! Drift velocity
XNORM=0.                ! Normalization constant
C
```

EXAMPLE: PROGRAM DRIFT

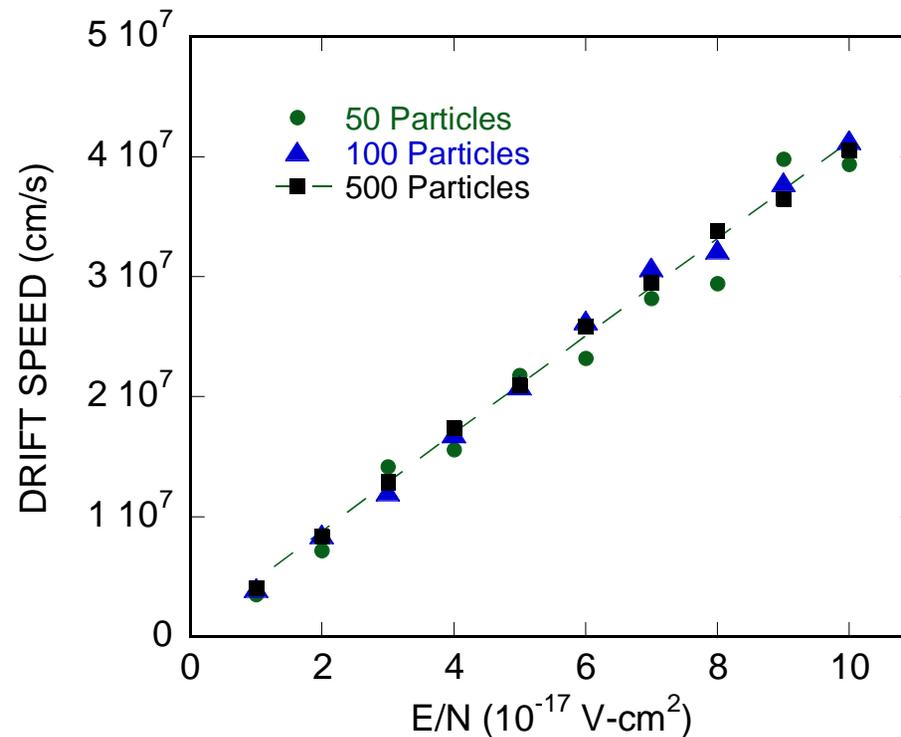
```
DO I=1,IELECTRONS
  X=0.
  TTOTAL=0.
  VX=0.
  VY=0.
  VZ=0.
C
C Randomly choose time to next collision
C
50 DT=-(1./COLF)*LOG(1.-RAN(1))
C
C Update position, speed of particle
C
  X=X+VX*DT+0.5*ACX*DT*DT
  VX=VX+ACX*DT
  TTOTAL=TTOTAL+DT
C
C Electron has not reached XEND. Perform Scatter
C
  IF (X.LT.XEND) THEN
    V=SQRT(VX**2+VY**2+VZ**2)
C
C Eulerian Angles
C
    BETA=ATAN2(VY,VX)
    ALPHA=ACOS(VZ/V)
C
C Randomly choose scattering angles
C
    THETA=ACOS(2.*RAN(2)-1.)
    PHI=2*PI*RAN(3)
```

EXAMPLE: PROGRAM DRIFT

```
C
C   Account for energy loss during elastic collision
C
C       V=V*SQRT(1.-(2.*XMASSE/XMASSN)*(1.-COS(THETA)))
C
C   Perform scatter
C
C       VX=V*(COS(BETA)*COS(ALPHA)*SIN(THETA)*COS(PHI)+
+         COS(BETA)*SIN(ALPHA)*COS(THETA)-SIN(BETA)*SIN(THETA)*SIN(PHI))
C       VY=V*(SIN(BETA)*COS(ALPHA)*SIN(THETA)*COS(PHI)+
+         SIN(BETA)*SIN(ALPHA)*COS(THETA)+COS(BETA)*SIN(THETA)*SIN(PHI))
C       VZ=V*(-SIN(ALPHA)*SIN(THETA)*COS(PHI)+COS(ALPHA)*COS(THETA))
C
C   Advance trajectories until the next collision
C
C       GO TO 50
C
C   END IF
C
C   Electron has drifted at least XEND
C
C       VDRIFT=VDRIFT+X/TTOTAL
C       XNORM=XNORM+1.
C   END DO
C
C   VDRIFT=VDRIFT/XNORM
C   PRINT *, 'VDRIFT=',VDRIFT,' cm/s'
C
C   END
```

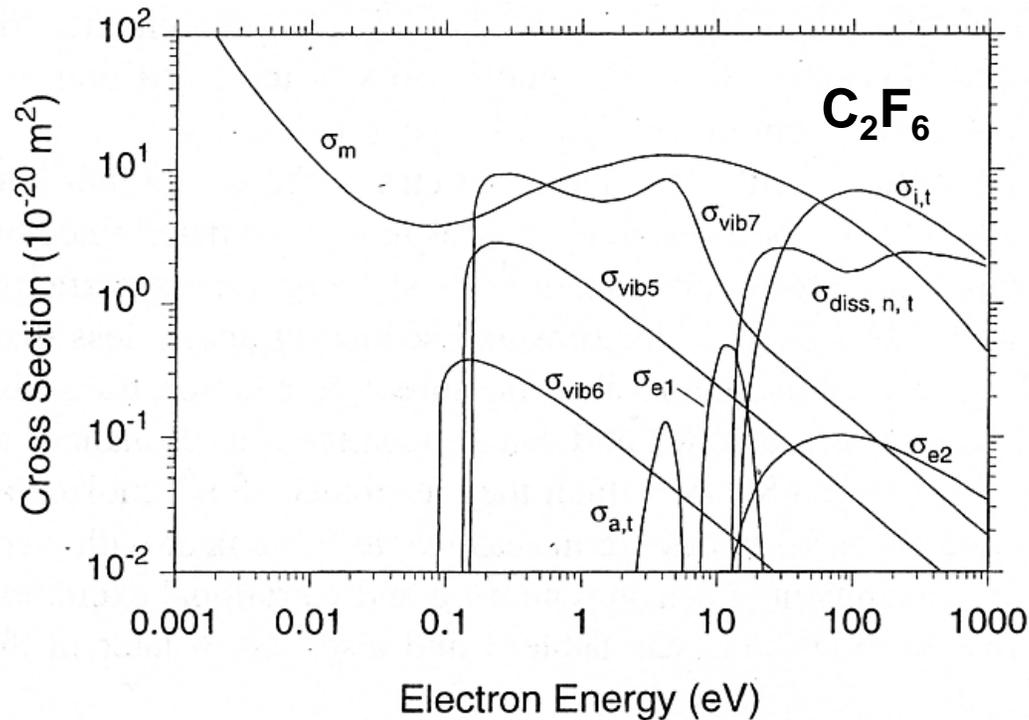
EXAMPLE: ELECTRON SWARM

- Collision frequency = $1.048 \times 10^9 \text{ s}^{-1}$
- Drift distance = 20 cm
- E/N (Electric field/gas number density) = $1-10 \times 10^{-17} \text{ V-cm}^3$
- Electron particles=50-500 per E/N



MUTIPLE COLLISIONS

- Real atoms/molecules have many electron collision processes (elastic, vibrational excitation, electronic excitation, ionization) with separate differential cross sections.

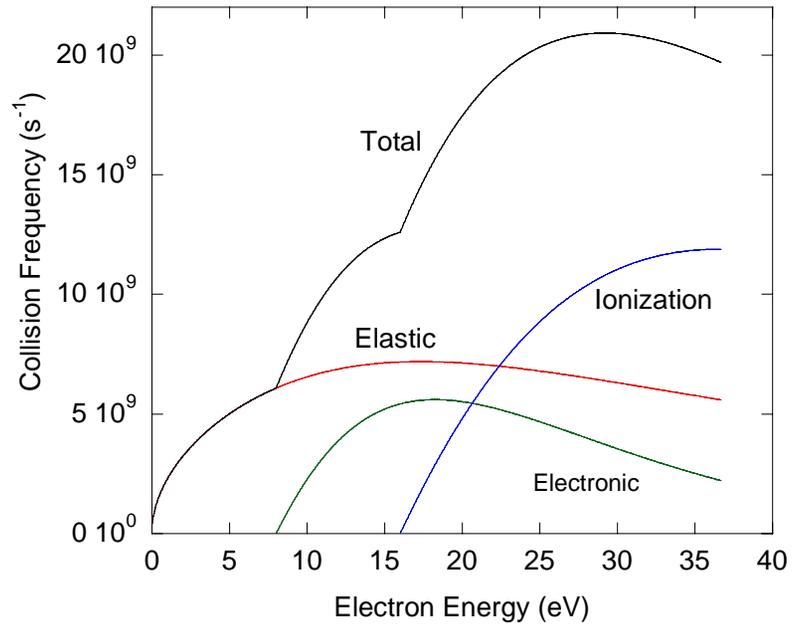
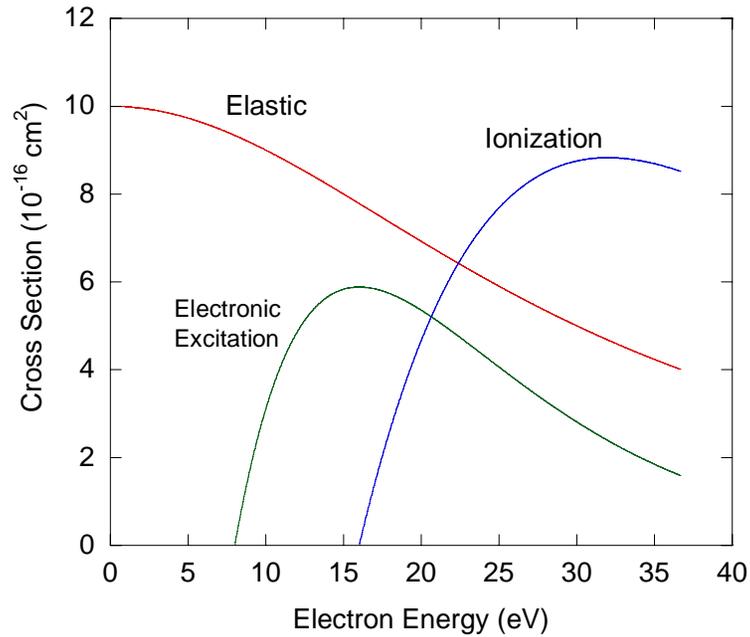


Christophorou, J. Chem. Phys. Ref. Data 27, 1, (1998)

- These processes can be statistically accounted for using MC techniques

University of Illinois
Optical and Discharge Physics

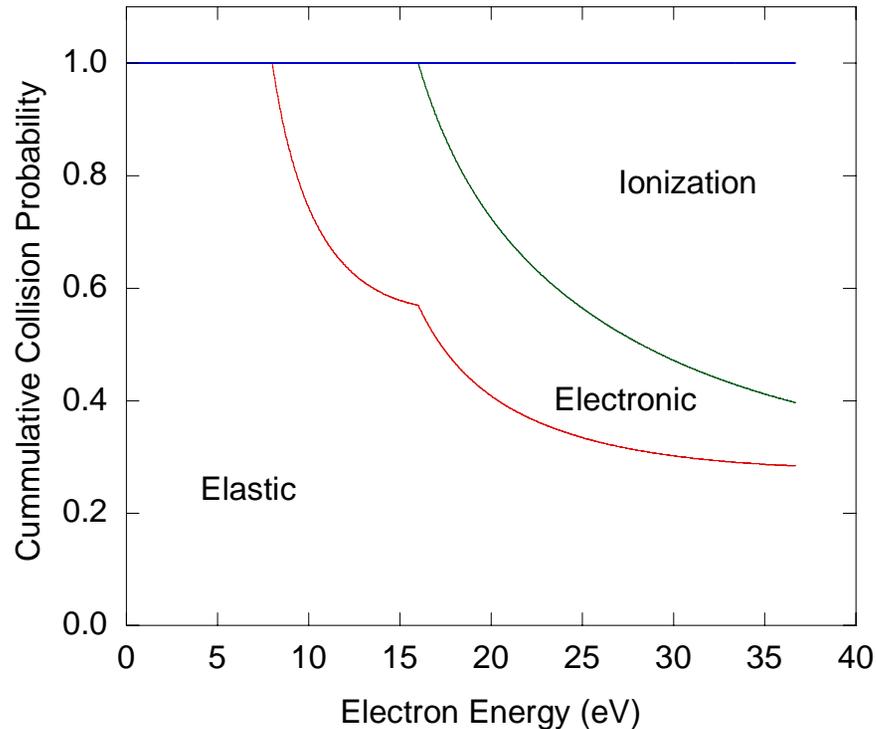
MODEL CROSS SECTIONS



- Compute collision frequencies for each process j having collision partner density N_j ,

$$v_j(\varepsilon) = \left(\frac{2\varepsilon}{m_e} \right)^{1/2} \sigma_j(\varepsilon) N_j, \quad v_{total}(\varepsilon) = \sum_j v_j(\varepsilon)$$

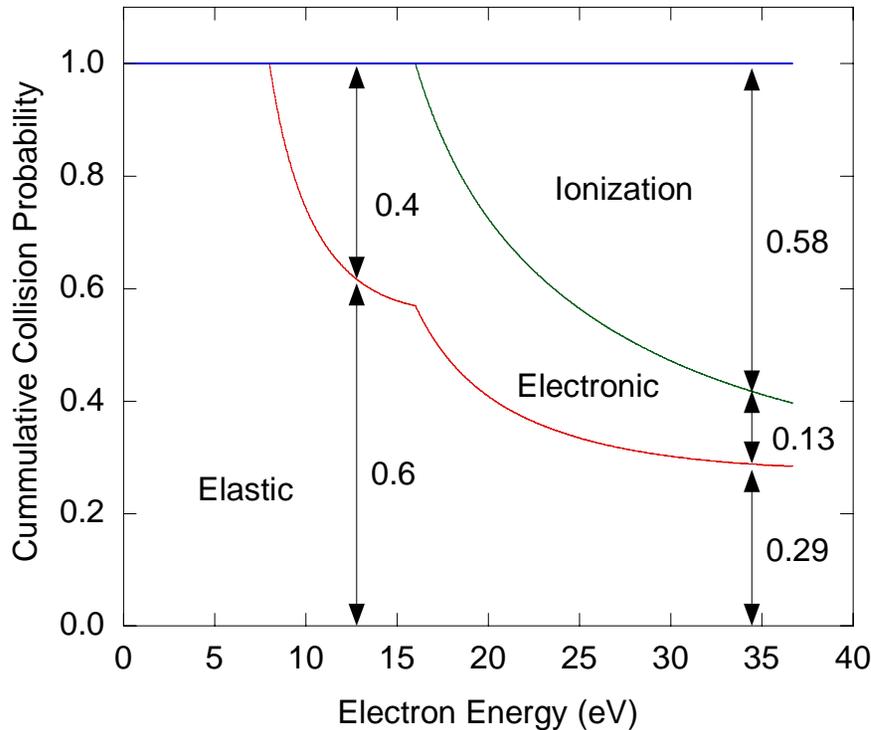
CUMULATIVE COLLISION PROBABILITY



$$p_j(\varepsilon) = \frac{\sum_{i=j-1}^j \nu_j(\varepsilon)}{\nu_{total}(\varepsilon)}$$

- **Cumulative collision probability is sum of probability of experiencing “yours” and all “previous” collisions. (Note: Order of summation is not important.)**

COLLISION SELECTION PROCESS



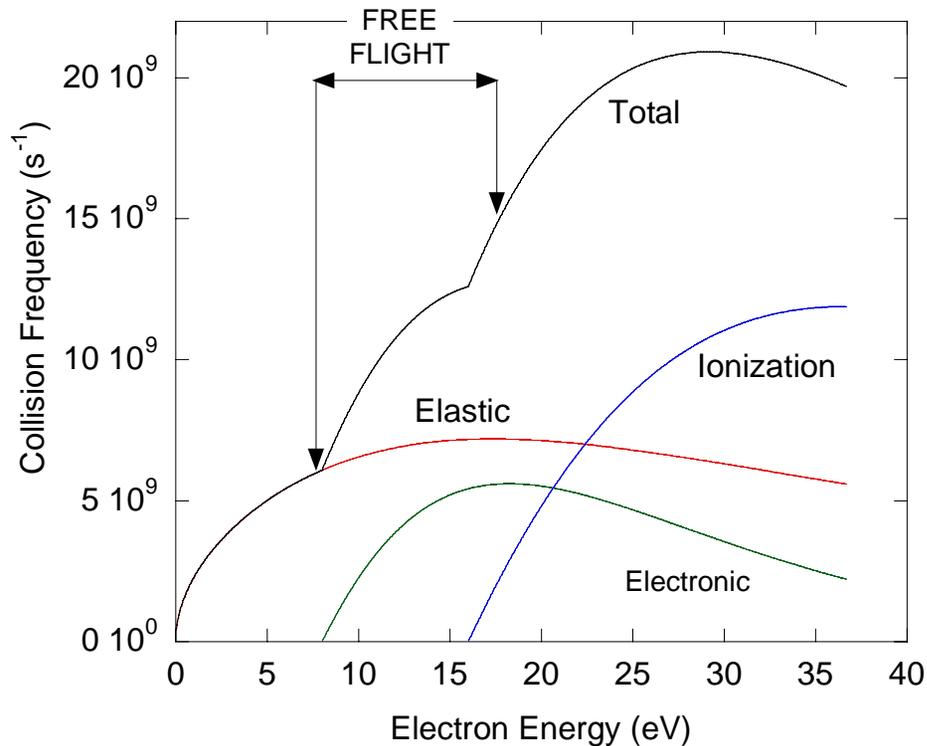
- Choose time between collisions based on total collision frequency.

$$\Delta t = \frac{-1}{\nu_{total}(\varepsilon)} \log(1 - r_1)$$

- The collision which occurs is that which satisfies

$$p_{j-1}(\varepsilon) < r_2 \leq p_j(\varepsilon)$$

NULL COLLISION FREQUENCY

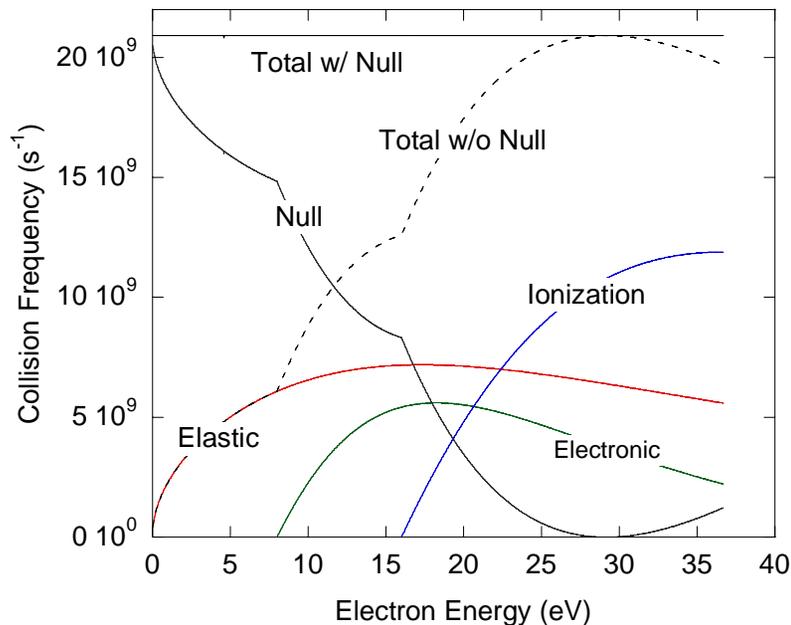


- The electron energy and collision frequency can change during the free flight between collisions.
- There is an ambiguity in choosing the time between collisions.
- The ambiguity is eliminated by the “null collision frequency” (NCF).

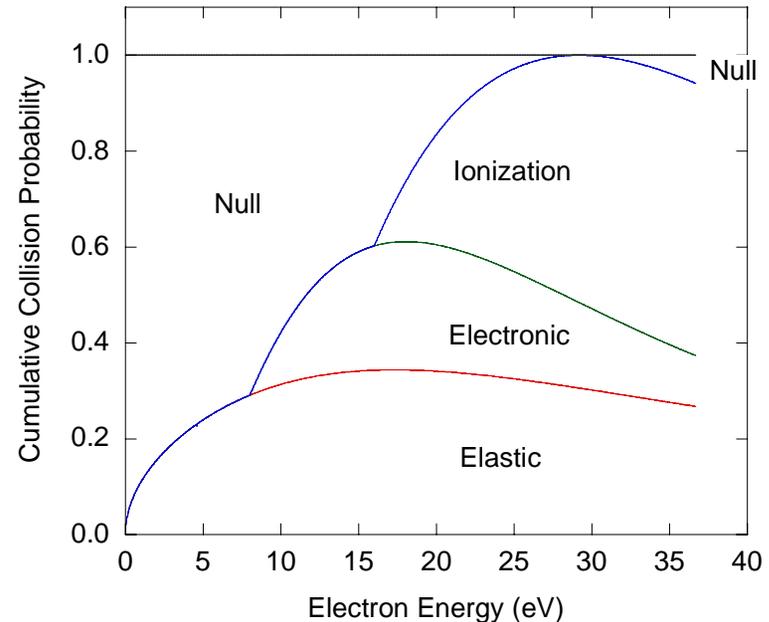
NULL COLLISION FREQUENCY

- The NCF is a fictitious process used to make it appear that all energies have the same collision frequency.

$$\nu_{null}(\varepsilon) = \text{Max}[\nu_{total}(\varepsilon)] - \nu_{total}(\varepsilon)$$

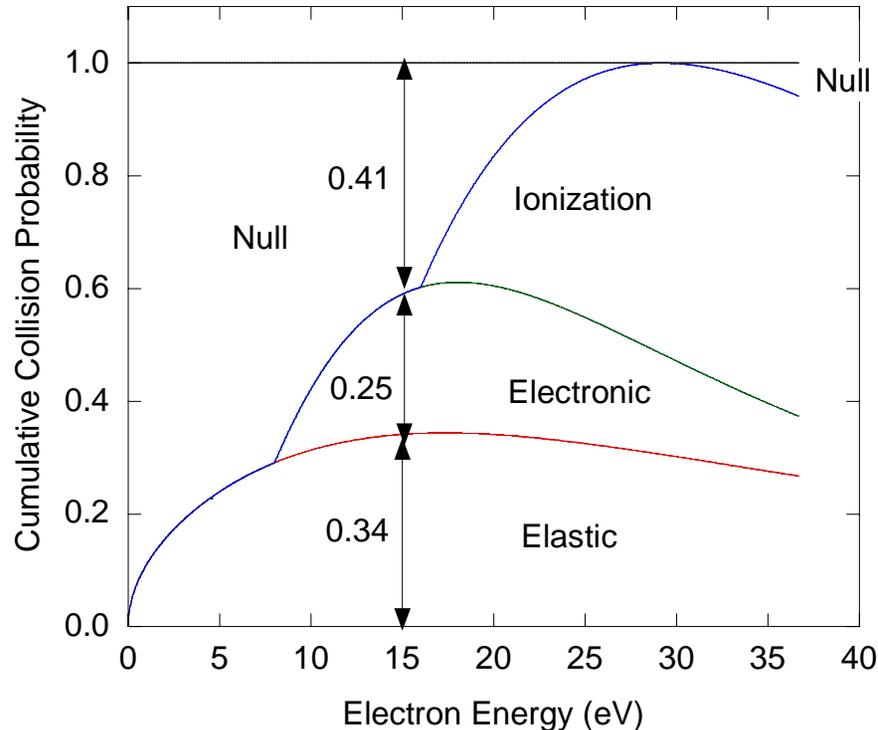


- **Collision frequencies with Null.**



- **Cumulative Probabilities with Null.**

COLLISION SELECTION PROCESS WITH NULL



- Choose time between collisions based on maximum total collision frequency.

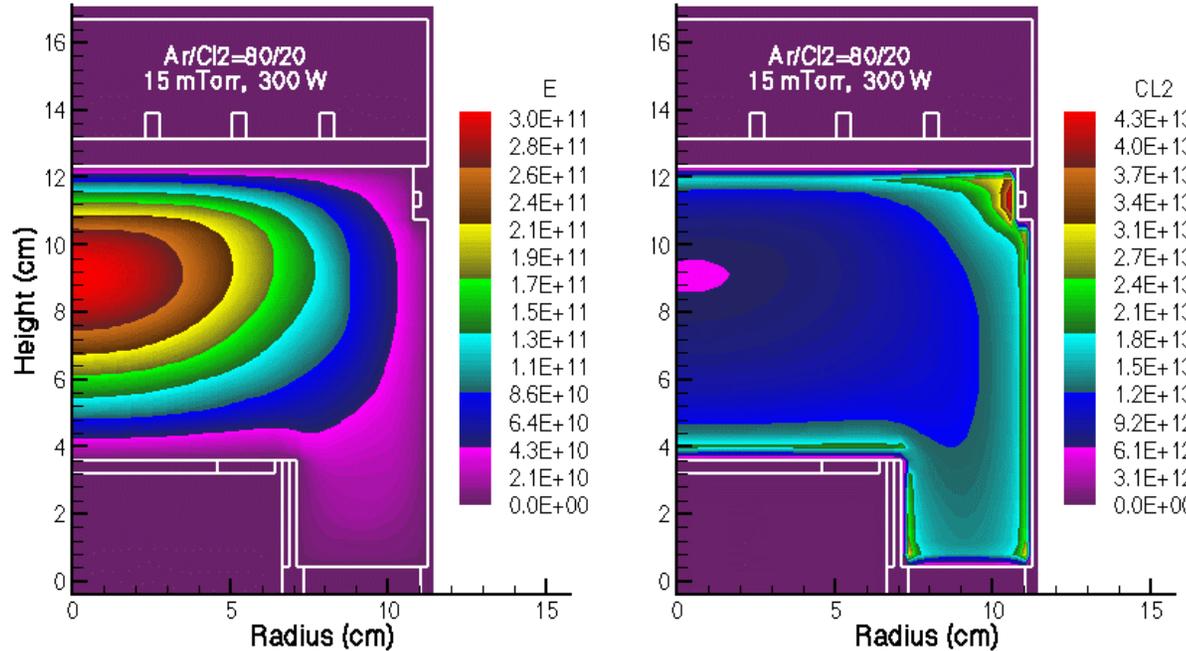
$$\Delta t = \frac{-1}{\text{Max}[v_{total}(\varepsilon)]} \log(1 - r_1)$$

- The collision which occurs is that which satisfies.

$$p_{j-1}(\varepsilon) < r_2 \leq p_j(\varepsilon)$$

- If the null is chosen, disregard the collision. Allow the electron to proceed to the next free flight without changing its velocity.

SPATIALLY VARYING COLLISION FREQUENCY



- [e] and Cl₂ densities in an ICP for etching (Ar/Cl₂=80/20, 15 mTorr)

- In many of the systems of interest, the density of the collision partner depends on position and time.

$$v_j(\varepsilon, x, t) = \left(\frac{2\varepsilon}{m_e} \right)^{1/2} \sigma_j(\varepsilon) N_j(x, t)$$

- The choice of $v_{total}(\varepsilon)$ can be ambiguous.

EXTENSION OF NULL METHOD TO ACCOUNT FOR $N(x,t)$

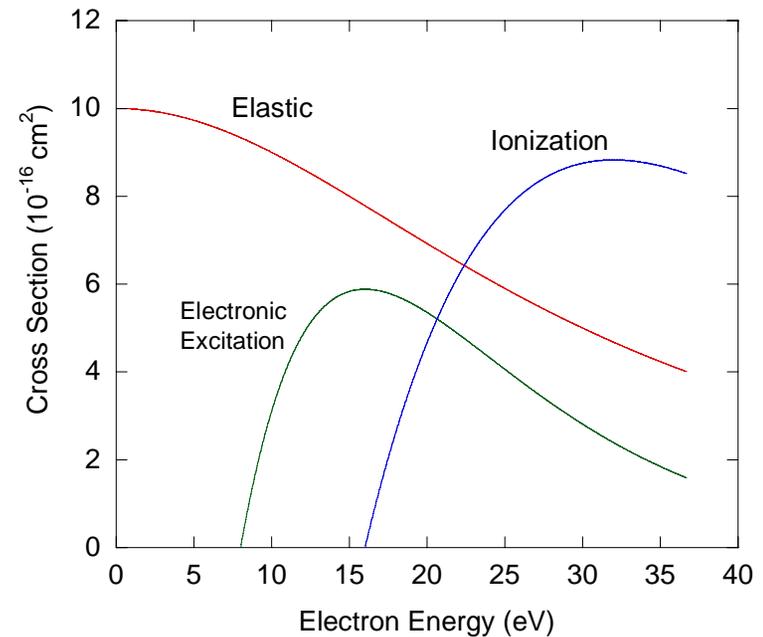
- **Sample time/space domain to determine $Max[N_j(x,t)]$.**
- **Compute $v_j(\varepsilon)$, $v_{total}(\varepsilon)$, $Max[v_{total}(\varepsilon)]$, $v_{null}(\varepsilon)$ using $Max[N_j(x,t)]$.**
- *Timestep* :
$$\Delta t = \frac{-1}{Max[v_{total}(\varepsilon, x)]} \log(1 - r_1)$$
- $x = x + v \cdot \Delta t$, $v = v + a \cdot \Delta t$
- *Collision* : $p_{j-1}(\varepsilon) < r_2 \leq p_j(\varepsilon)$
- $j = Null \rightarrow next\ trajectory$
- $r_3 > \frac{N_j(x,t)}{Max[N_j(x,t)]} \rightarrow Null \rightarrow next\ trajectory$
- *scattering* $(\theta, \phi) = F^{-1}(r_4, r_5)$
- *Scattering Matrix*

SAMPLING AND INTEGRATION METHODS

- Electron distributions are obtained by sampling the particle trajectories; binning particles by energy, velocity, position to obtain $f(\varepsilon, \vec{r}, t)$ or $f(\vec{v}, \vec{r}, t)$.
- How you sample affects the distribution function you derive.
- Integration Δt should be less than: Δt_{col} , fraction of $1/v_{\text{rf}}$, fraction of $\left[\frac{v}{E} \frac{dE}{dx}\right]^{-1}$ or other constraining frequencies.
- Δt can be different for each particle. Particles can “diverge in time” until they reach a time when they must be coincident.
- Recommended sampling and integration strategy:
 - Choose $t(\text{next collision}) = t(\text{last collision}) + \Delta t_{\text{col}}$
 - Integrate using $\Delta t \leq t - t(\text{next collision})$
 - Sample particles for every Δt weighting the contribution by Δt .
 - When reach $t(\text{next collision})$, collide and choose new Δt_{col}

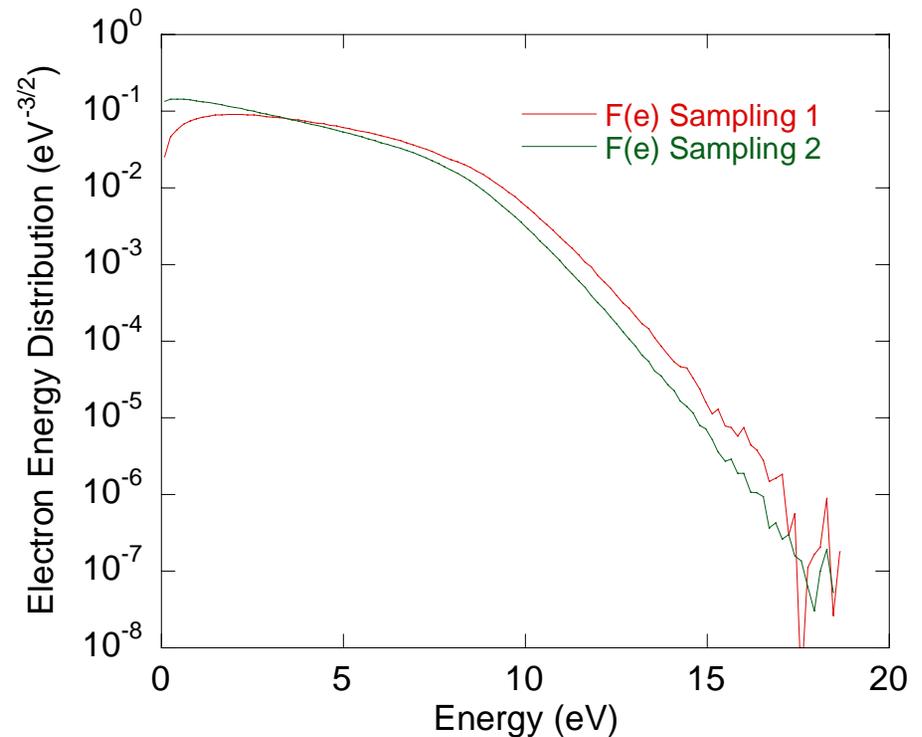
EXAMPLE: ELECTRON ENERGY DISTRIBUTION

- Compute electron energy distribution and rate coefficients for idealized cross sections.
- Conditions:
 - E/N : $100 \times 10^{-17} \text{ V-cm}^2$ (100 Td)
 - Drift distance: 3 cm (sample after 0.5 cm)
 - Number of Particles: 2000



EXAMPLE: ELECTRON ENERGY DISTRIBUTION

- Sampling method
 - 1: Every Δt_{col}
 - 2: Every Δt (constant) $< \Delta t_{\text{col}}$
- Rate Coefficients (cm^3/s)
 - Elastic 1.1×10^{-7}
 - Electronic 2.0×10^{-9}
 - Ionization 9.9×10^{-14}
- Number of Collisions:
 - Elastic 1.46×10^7
 - Electronic 2.21×10^5
 - Ionization 10
 - Null 5.93×10^7

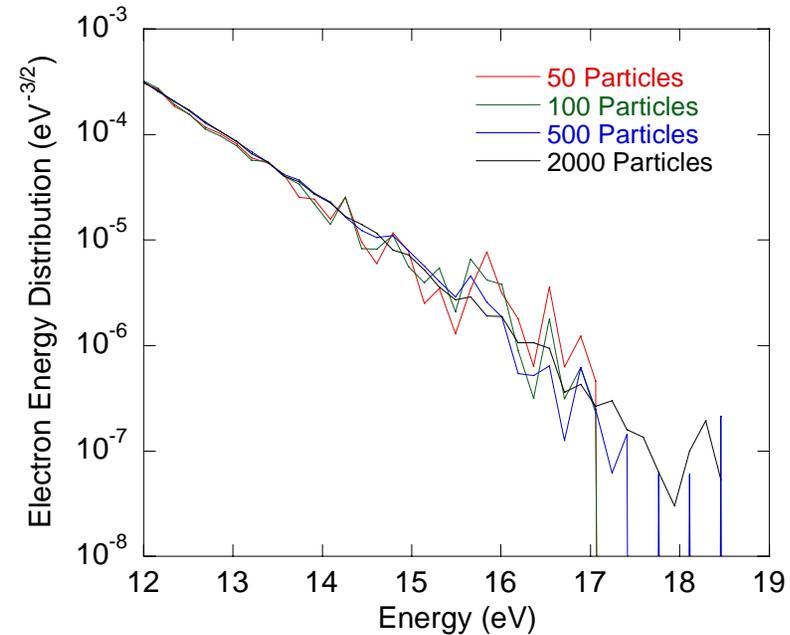
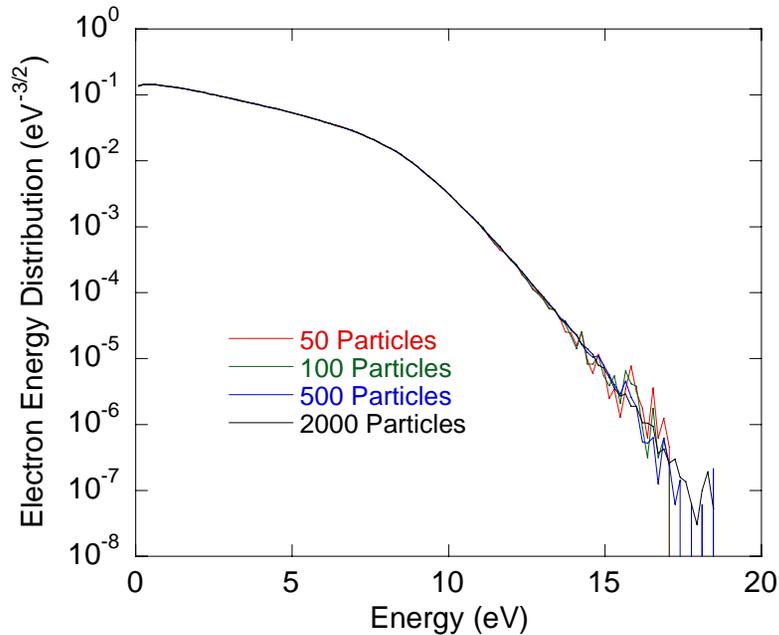


- Lesson!!! Do NOT compute rate coefficients by counting collisions! Directly compute rate coefficients from EED.

$$k(\vec{r}, t) = \int f(\varepsilon, \vec{r}, t) \left(\frac{2\varepsilon}{m_e} \right)^{1/2} \sigma(\varepsilon) \varepsilon^{1/2} d\varepsilon$$

EXAMPLE: ELECTRON ENERGY DISTRIBUTION

- Required samplings are dictated by the tail of the EED. Rate coefficients for high threshold events are sensitive to the tail.



Number of Particles	50	100	500	2000
Rate Coefs: Elastic	1.08×10^{-7}	1.08×10^{-7}	1.08×10^{-7}	1.08×10^{-7}
Electronic ($\Delta\varepsilon = 8$ eV)	1.98×10^{-9}	1.99×10^{-9}	2.00×10^{-9}	1.99×10^{-9}
Ionization ($\Delta\varepsilon = 16$ eV)	1.23×10^{-13}	6.51×10^{-14}	6.84×10^{-14}	9.94×10^{-14}
Samplings	2,953,842	5,899,608	29,327,876	117,332,716

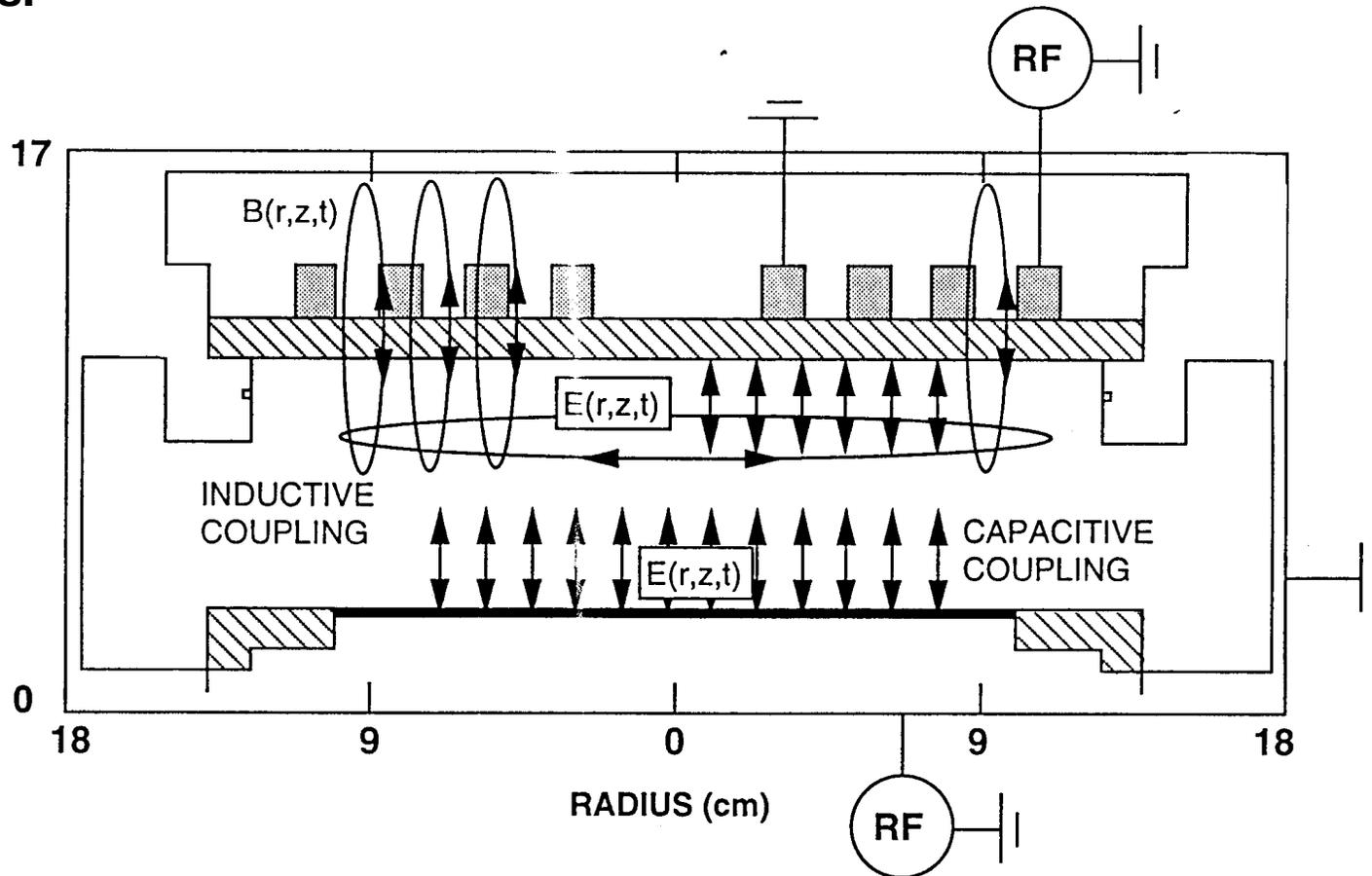
EFFICIENCY ISSUES

- Create look-up tables where-ever possible (memory and lookups are cheap, computations are expensive).
- Minimize null-collisions by having sub-intervals of energy range with different $Max[v_{total}(\epsilon)]$.
- Be cognizant of “pipelining” opportunities. Perform array operations with stencils to include-exclude indices for particles which are added-removed due to attachment, losses to walls or ionization.
- Take advantage of cyclic conditions to bin particles by phase as opposed to time.
- NEVER hardwire anything!! Define all cross sections, densities from “outside.”

ADVANCED TOPICS

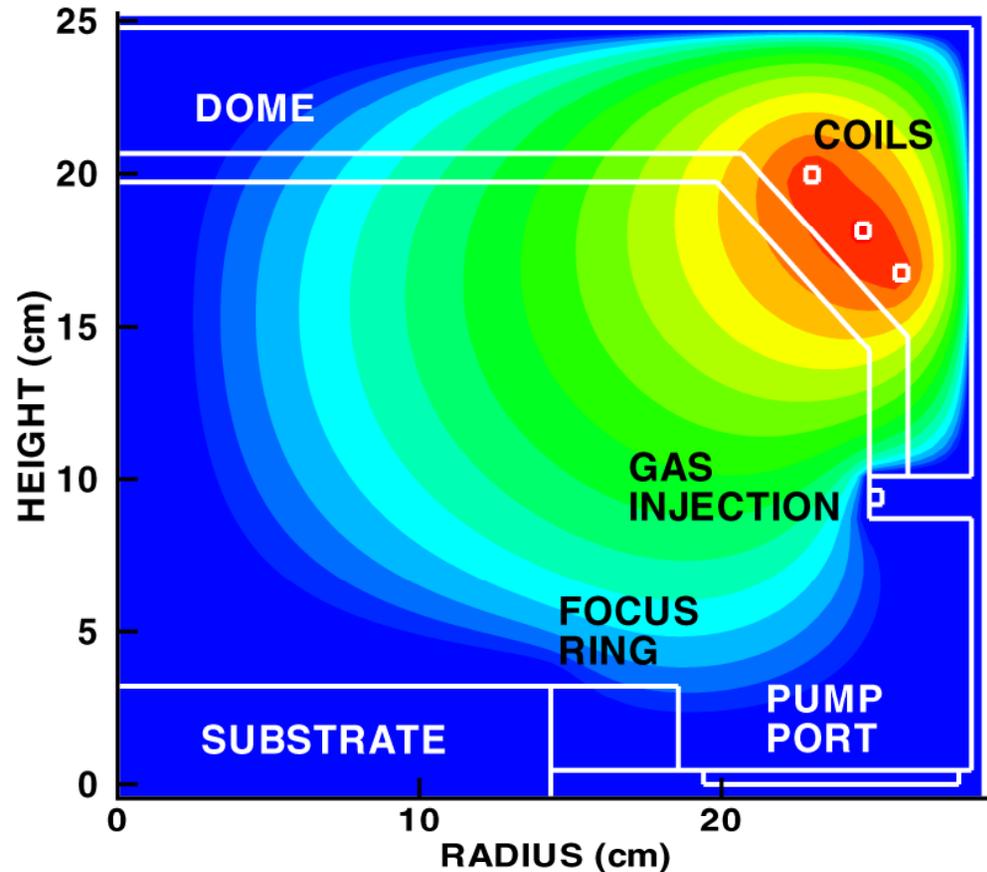
TYPICAL INDUCTIVELY COUPLED PLASMA FOR ETCHING

- Power is coupled into the plasma by both inductive and capacitive routes.



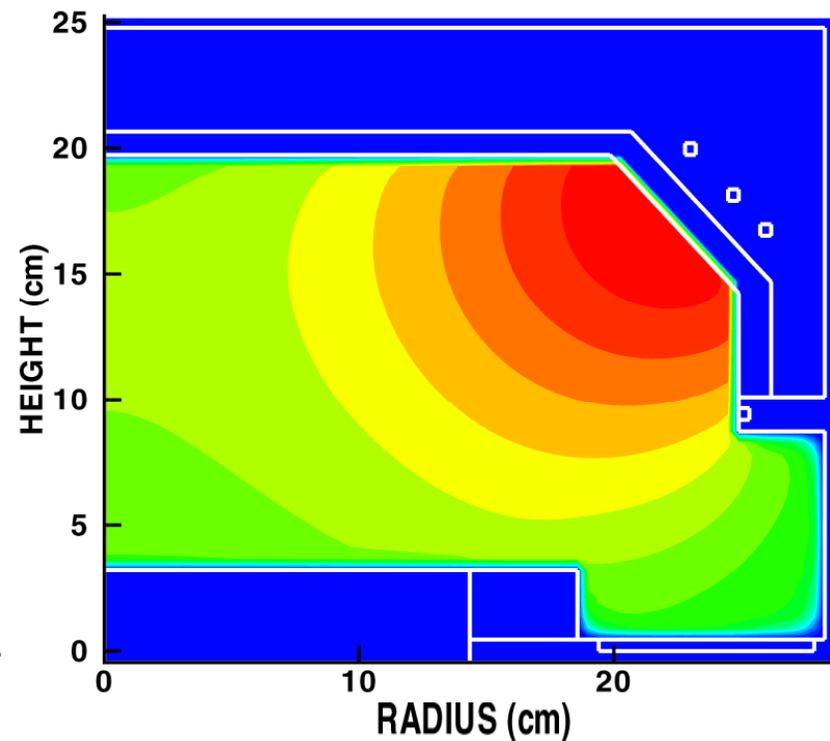
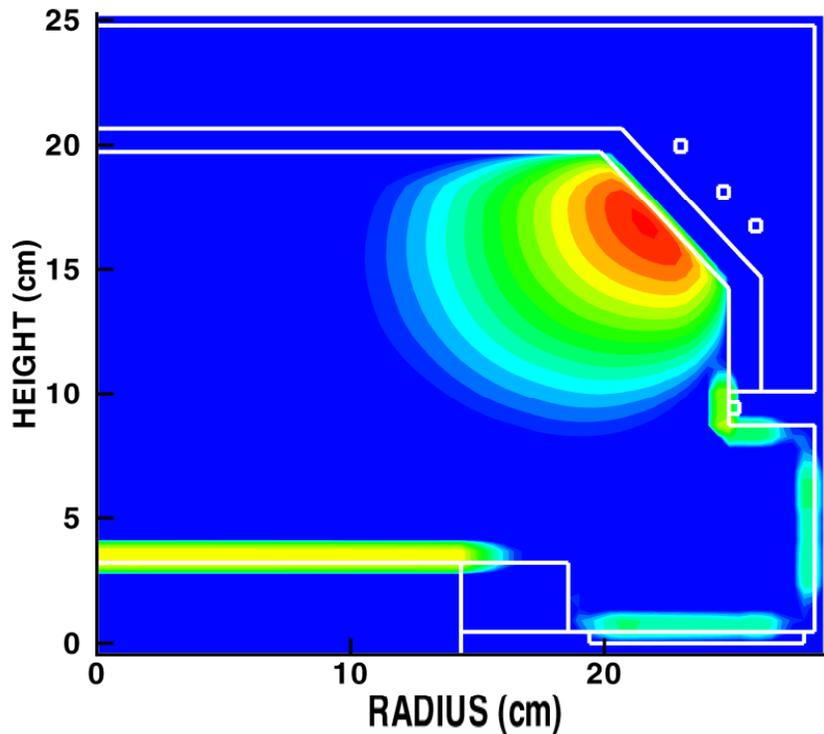
WALK THROUGH: Ar/Cl₂ PLASMA FOR p-Si ETCHING

- The inductively coupled electromagnetic fields have a skin depth of 3-4 cm.
- Absorption of the fields produces power deposition in the plasma.
- Electric Field (max = 6.3 V/cm)
 - Ar/Cl₂ = 80/20
 - 20 mTorr
 - 1000 W ICP 2 MHz
 - 250 V bias, 2 MHz (260 W)



Ar/Cl₂ ICP: POWER AND ELECTRON TEMPERATURE

- ICP Power heats electrons, capacitively coupled power dominantly accelerates ions.

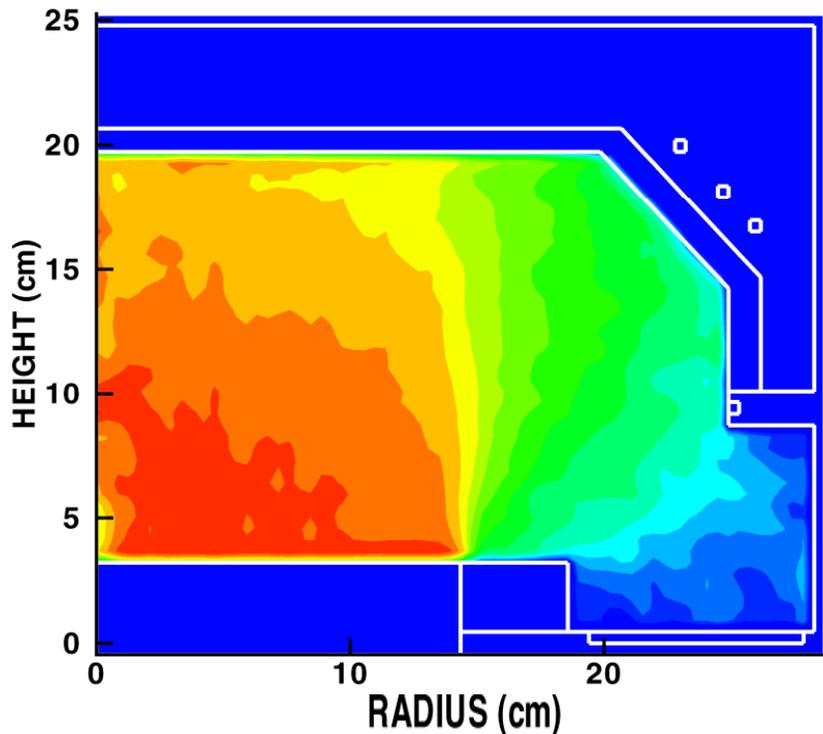


- Power Deposition (max = 0.9 W/cm³)
- Electron Temperature (max = 5 eV)

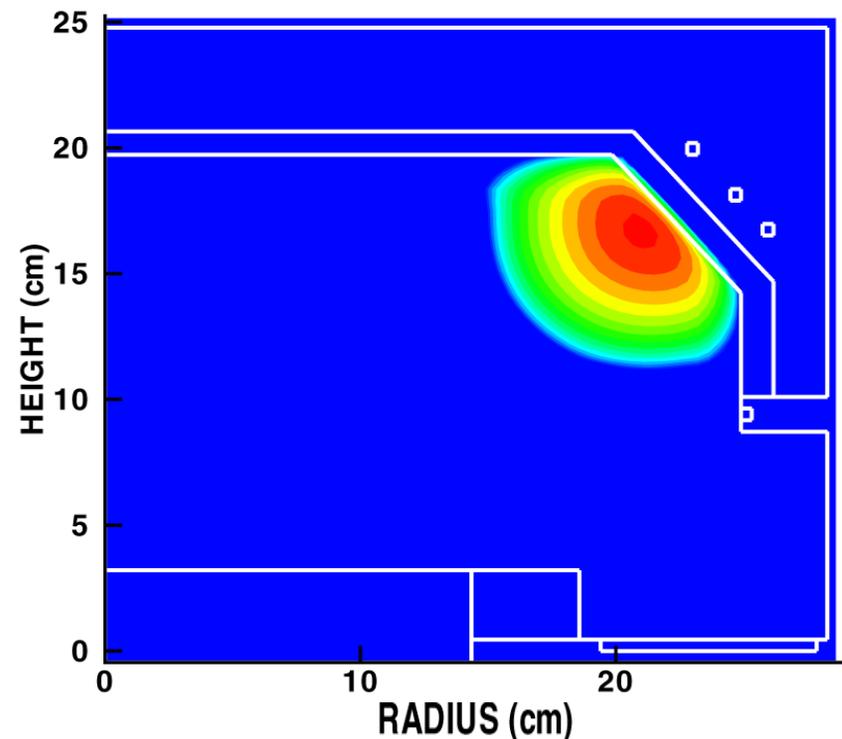
- Ar/Cl₂ = 80/20, 20 mTorr, 1000 W ICP 2 MHz, 250 V bias, 2 MHz (260 W)

Ar/Cl₂ ICP: IONIZATION

- Ionization is produced by bulk electrons and sheath accelerated secondary electrons.



- Beam Ionization
(max = $1.3 \times 10^{14} \text{ cm}^{-3}\text{s}^{-1}$)

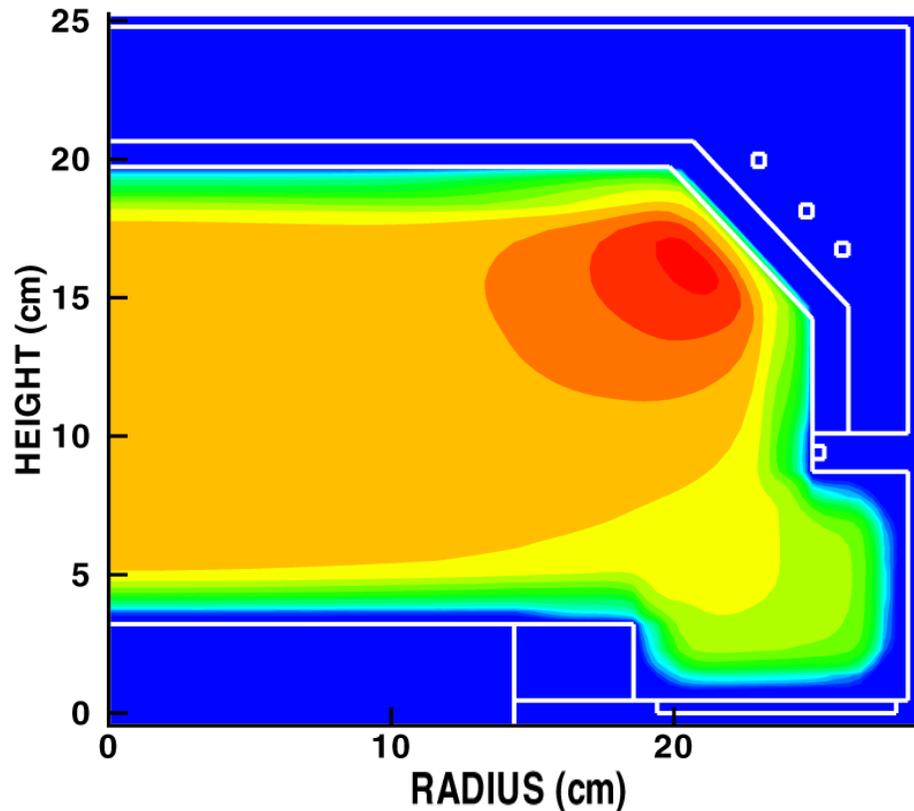


- Bulk Ionization
(max = $5.4 \times 10^{15} \text{ cm}^{-3}\text{s}^{-1}$)

- Ar/Cl₂ = 80/20, 20 mTorr, 1000 W ICP 2 MHz,
250 V bias, 2 MHz (260 W)

Ar/Cl₂ ICP: POSITIVE ION DENSITY

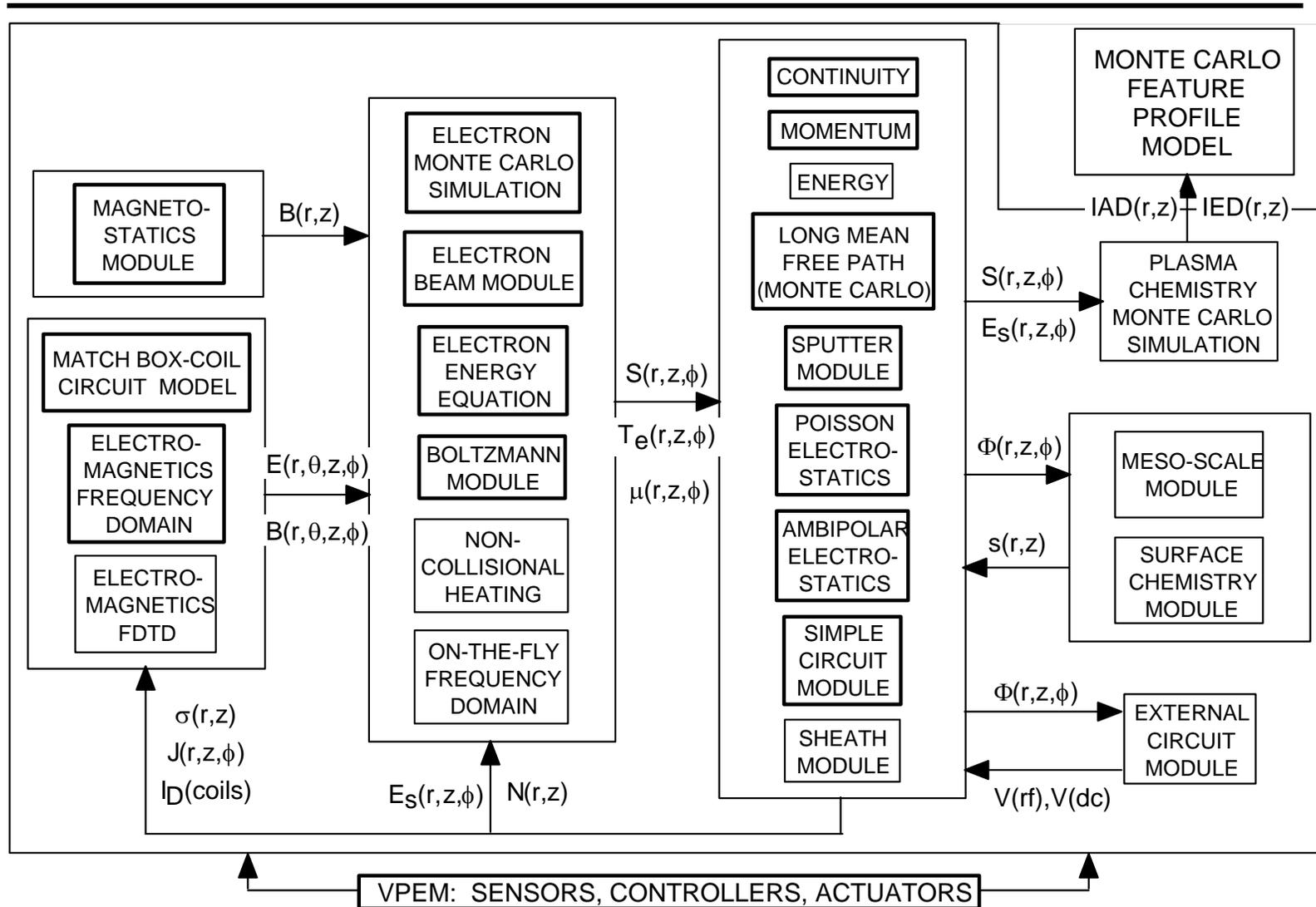
- Diffusion from the remote plasma source produces uniform ion densities at the substrate.



- Positive Ion Density
(max = $1.8 \times 10^{11} \text{ cm}^{-3}$)

- Ar/Cl₂ = 80/20, 20 mTorr, 1000 W ICP 2 MHz,
250 V bias, 2 MHz (260 W)

HYBRID PLASMA EQUIPMENT MODEL



University of Illinois
Optical and Discharge Physics

ELECTROMAGNETICS MODEL

- The wave equation is solved in the frequency domain using sparse matrix techniques (2D,3D):

$$-\nabla \cdot \left(\frac{1}{\mu} \nabla \cdot \bar{\mathbf{E}} \right) + \nabla \cdot \left(\frac{1}{\mu} \nabla \bar{\mathbf{E}} \right) = \frac{\partial^2 (\epsilon \bar{\mathbf{E}})}{\partial t^2} + \frac{\partial (\bar{\boldsymbol{\sigma}} \cdot \bar{\mathbf{E}} + \bar{\mathbf{J}})}{\partial t}$$

$$\vec{\mathbf{E}}(\vec{r}, t) = \vec{\mathbf{E}}'(\vec{r}) \exp(-i(\omega t + \varphi(\vec{r})))$$

- Conductivities are tensor quantities (2D,3D):

$$\bar{\boldsymbol{\sigma}} = \sigma_o \frac{m v_m}{q \alpha} \frac{1}{\left(\alpha^2 + |\vec{\mathbf{B}}|^2 \right)} \begin{pmatrix} \alpha^2 + B_r^2 & \alpha B_z + B_r B_\theta & -\alpha B_\theta + B_r B_z \\ -\alpha B_z + B_r B_\theta & \alpha^2 + B_\theta^2 & \alpha B_r + B_\theta B_z \\ -\alpha B_\theta + B_r B_z & -\alpha B_r + B_\theta B_z & \alpha^2 + B_z^2 \end{pmatrix}$$

$$\vec{\mathbf{j}} = \bar{\boldsymbol{\sigma}} \cdot \vec{\mathbf{E}} \quad \alpha = \frac{(i\omega + v_m)}{q/m}, \quad \sigma_o = \frac{q^2 n_e}{m v_m}$$

ELECTROMAGNETICS MODEL (cont.)

- The electrostatic term in the wave equation is addressed using a perturbation to the electron density (2D).

$$\nabla \cdot \bar{E} = \frac{\rho}{\epsilon} = \frac{q\Delta n_e}{\epsilon}, \quad \Delta n_e = -\nabla \cdot \left(\frac{\bar{\sigma} \cdot \bar{E}}{q} \right) / \left(\frac{1}{\tau} + i\omega \right)$$

- Conduction currents can be kinetically derived from the Electron Monte Carlo Simulation to account for non-collisional effects (2D).

$$J_e(\vec{r}, t) = J_o(\vec{r}) \exp(i(\omega t + \phi_v(\vec{r}))) = -qn_e(\vec{r})\vec{v}_e(\vec{r}) \exp(i(\omega t + \vec{\phi}_v(\vec{r})))$$

ELECTRON ENERGY TRANSPORT

- **Continuum (2D,3D):**

$$\partial \left(\frac{3}{2} n_e k T_e \right) / \partial t = S(T_e) - L(T_e) - \nabla \cdot \left(\frac{5}{2} \Phi k T_e - \bar{\kappa}(T_e) \cdot \nabla T_e \right) + S_{EB}$$

where $S(T_e)$	=	Power deposition from electric fields
$L(T_e)$	=	Electron power loss due to collisions
Φ	=	Electron flux
$\kappa(T_e)$	=	Electron thermal conductivity tensor
S_{EB}	=	Power source source from beam electrons

- Power deposition has contributions from wave and electrostatic heating.
- **Kinetic (2D,3D):** A Monte Carlo Simulation is used to derive $f(\varepsilon, \vec{r}, t)$ including electron-electron collisions using electromagnetic fields from the EMM and electrostatic fields from the FKM.

PLASMA CHEMISTRY, TRANSPORT AND ELECTROSTATICS

- Continuity, momentum and energy equations are solved for each species (with jump conditions at boundaries) (2D,3D).

$$\frac{\partial N_i}{\partial t} = -\nabla \cdot (N_i \vec{v}_i) + S_i$$

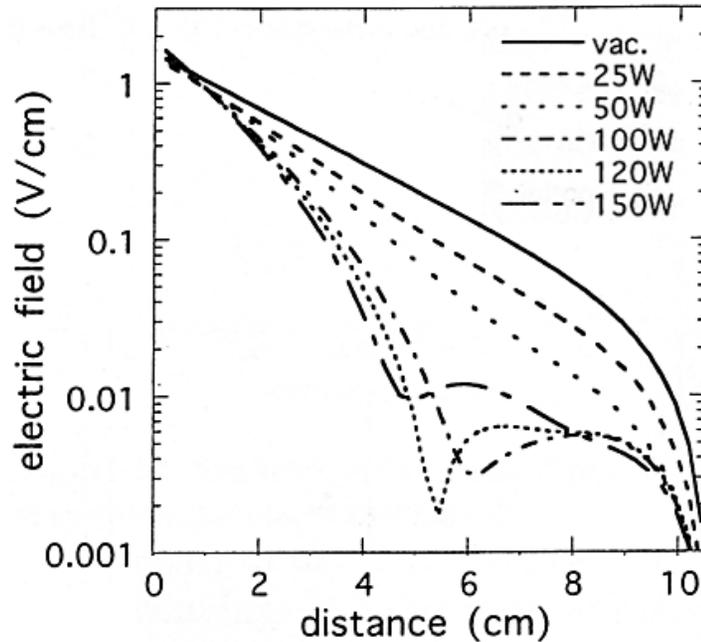
$$\frac{\partial (N_i \vec{v}_i)}{\partial t} = \frac{1}{m_i} \nabla (k N_i T_i) - \nabla \cdot (N_i \vec{v}_i \vec{v}_i) + \frac{q_i N_i}{m_i} (\vec{E} + \vec{v}_i \times \vec{B}) - \nabla \cdot \bar{\mu}_i - \sum_j \frac{m_j}{m_i + m_j} N_i N_j (\vec{v}_i - \vec{v}_j) \nu_{ij}$$

$$\begin{aligned} \frac{\partial (N_i \varepsilon_i)}{\partial t} + \nabla \cdot \mathbf{Q}_i + P_i \nabla \cdot \mathbf{U}_i + \nabla \cdot (N_i \mathbf{U}_i \varepsilon_i) &= \frac{N_i q_i^2 \nu_i}{m_i (\nu_i^2 + \omega^2)} E^2 \\ &+ \frac{N_i q_i^2}{m_i \nu_i} E_s^2 + \sum_j 3 \frac{m_{ij}}{m_i + m_j} N_i N_j R_{ij} k_B (T_j - T_i) \pm \sum_j 3 N_i N_j R_{ij} k_B T_j \end{aligned}$$

- Implicit solution of Poisson's equation (2D,3D):

$$\nabla \cdot \varepsilon \nabla \Phi(t + \Delta t) = - \left(\rho_s + \sum_i q_i N_i - \Delta t \cdot \sum_i (q_i \nabla \cdot \vec{\phi}_i) \right)$$

ANAMOLOUS SKIN EFFECT AND POWER DEPOSITION



- Collisional heating:

$$\lambda_{mfp} < \delta_{skin}, \quad \vec{J}_e(\vec{r}, t) = \sigma(\vec{r}, t) \vec{E}(\vec{r}, t)$$

- Anomalous skin effect:

$$\lambda_{mfp} > \delta_{skin}$$

$$\vec{J}_e(\vec{r}, t) = \iint \sigma(\vec{r}, \vec{r}', t, t') \vec{E}(\vec{r}', t') d\vec{r}' dt'$$

$$\vec{F} = \bar{v} \times \vec{B}$$

- Ref: V. Godyak, “Electron Kinetics of Glow Discharges”

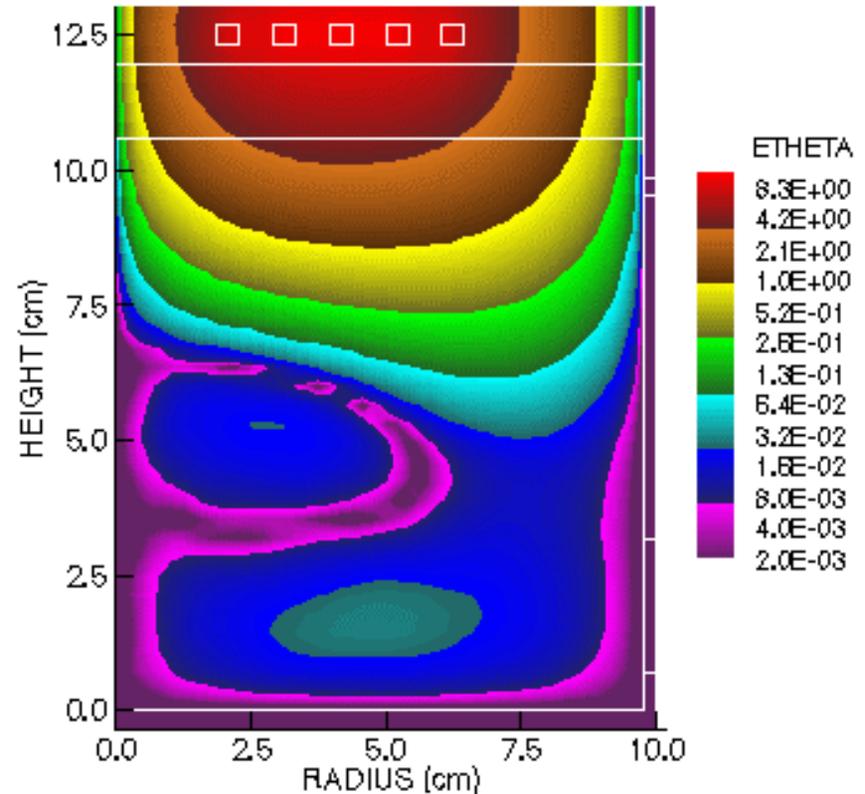
- Electrons receive (positive) and deliver (negative) power from/to the E-field.
- E-field is non-monotonic.

COLLISIONLESS TRANSPORT ELECTRIC FIELDS

- We capture these effects by kinetically deriving electron current.

$$\oint \vec{j}(\vec{r}) \exp(i\omega(t - t_o)) \cdot dA = \sum_k q_k \vec{v}_k(\vec{r}) \exp(i\omega(t_k - t_o))$$

- E_θ during the rf cycle exhibits extrema and nodes resulting from this non-collisional transport.
- “Sheets” of electrons with different phases provide current sources interfering or reinforcing the electric field for the next sheet.
- Axial transport results from $\vec{v} \times \vec{B}_{rf}$ forces.

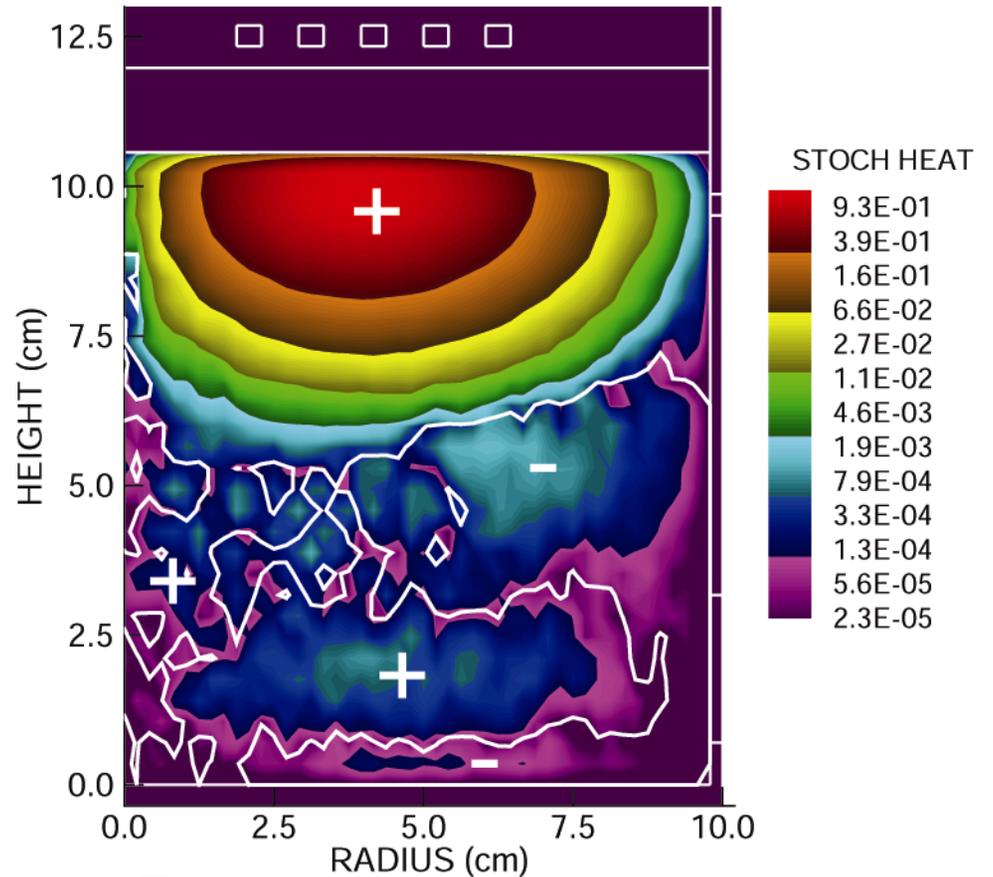
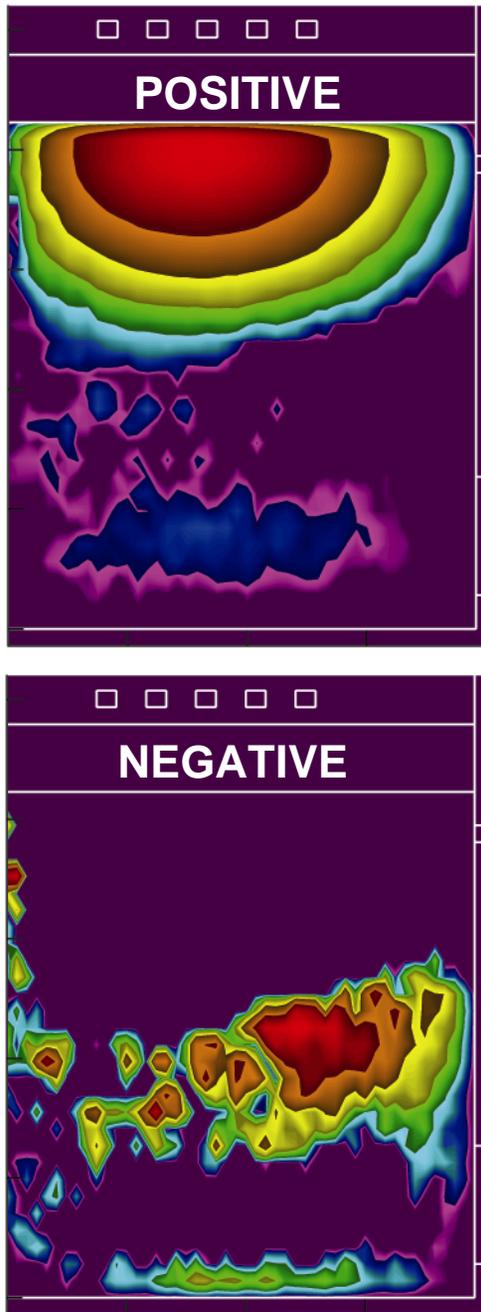


ANIMATION SLIDE

- Ar, 10 mTorr, 7 MHz, 100 W

POWER DEPOSITION: POSITIVE AND NEGATIVE

- The end result is regions of positive and negative power deposition.

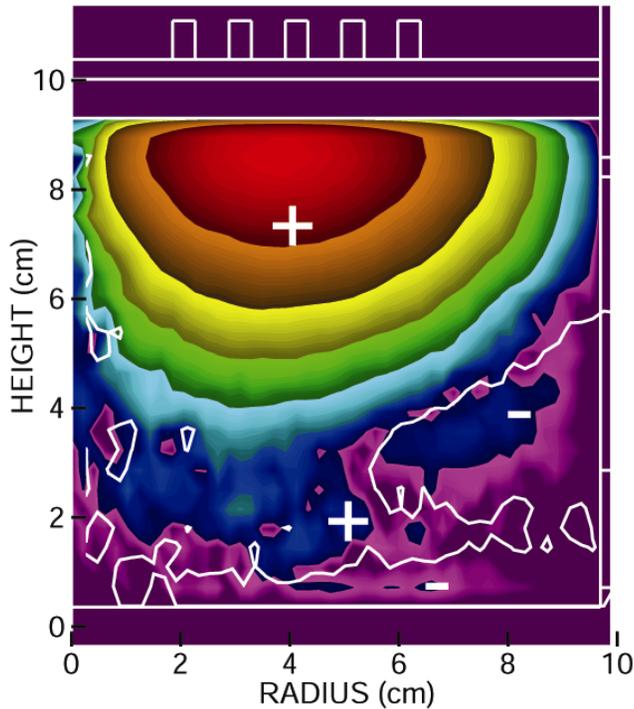


- Ar, 10 mTorr,
7 MHz, 100 W

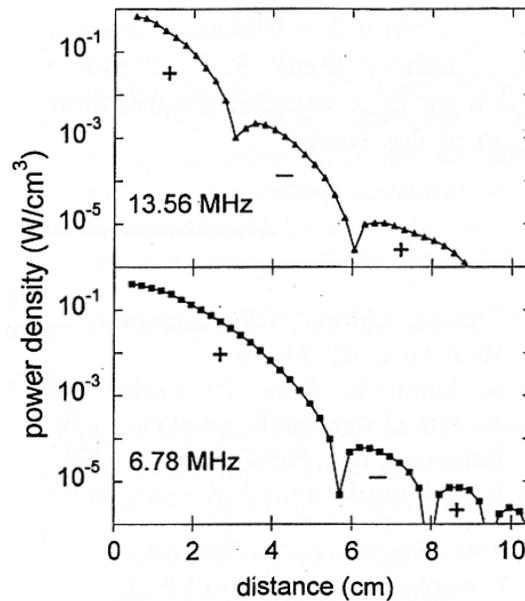
University of Illinois
Optical and Discharge Physics

POWER DEPOSITION vs FREQUENCY

- The shorter skin depth at high frequency produces more layers of negative power deposition of larger magnitude.

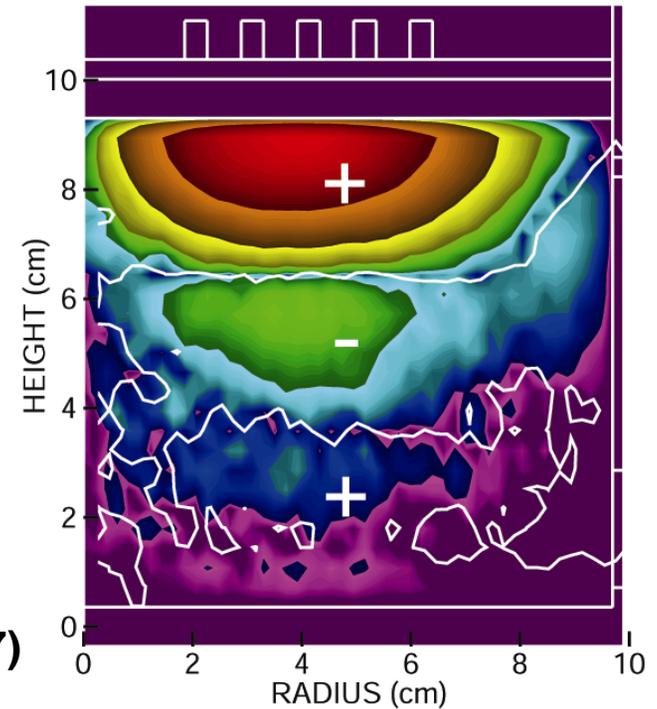


• **6.7 MHz**
 ($5 \times 10^{-5} - 1.4 \text{ W/cm}^3$)



• Ref: Godyak, PRL (1997)

• Ar, 10 mTorr, 200 W



• **13.4 MHz**
 ($8 \times 10^{-5} - 2.2 \text{ W/cm}^3$)



TIME DEPENDENCE OF EEDs: FOURIER ANALYSIS

- To obtain time dependent EEDs, Fourier transforms are performed “on-the-fly” in the Electron Monte Carlo Simulation.
- As electron trajectories are integrated, complex Fourier coefficients and weightings are incremented by.

$$\Delta\Psi_n(\varepsilon_i, \vec{r}_k) = \sum_j w_j \Delta t_j \exp(in\omega t_j) \delta((\varepsilon_i \pm \frac{1}{2} \Delta\varepsilon_i) - \varepsilon_j) \sum_k \delta((\vec{r}_{l+k} \pm \frac{1}{2} \Delta\vec{r}_{l+k}) - \vec{r}_j),$$
$$\Delta W_{jk} = \sum_j w_j \Delta t_j \sum_k \delta((\vec{r}_{l+k} \pm \frac{1}{2} \Delta\vec{r}_{l+k}) - \vec{r}_j)$$

- The Fourier coefficients are then obtained from:

$$A_n(\varepsilon_i, \vec{r}_k) = \left| \frac{\Psi_n(\varepsilon_i, \vec{r}_k)}{W_{ik}} \right|, \quad \phi_n(\varepsilon_i, \vec{r}_k) = \tan^{-1} \left(\frac{\text{Im}[\Psi_n(\varepsilon_i, \vec{r}_k)]}{\text{Re}[\Psi_n(\varepsilon_i, \vec{r}_k)]} \right)$$

TIME DEPENDENCE OF EEDs: FOURIER ANALYSIS

- The time dependence of the n^{th} harmonic of the EED is then reconstructed

$$f_n(\varepsilon, \vec{r}, t) = A_n(\varepsilon, \vec{r}) \sin[\omega n t + \phi_n(\varepsilon, \vec{r})]$$

- ...and the total time dependence of the electron distribution function is obtain from summation of the harmonics:

$$f(\varepsilon, \vec{r}, t) = \sum_{n=0}^N f_n(\varepsilon, \vec{r}, t)$$

....where f_0 is the time averaged distribution function.

EXCITATION RATES: “ON THE FLY”

- In a similar manner, Fourier components of excitation rates can be obtained directly from the Electron MCS
- For the n^{th} harmonic of the m^{th} process,

$$k'_{nml} \rightarrow k_{nml} + \sum_j w_j \sigma_m(\varepsilon_j) v_j \exp(in\omega t) \sum_k \delta((\vec{r}_{l+k} \pm \frac{1}{2} \Delta\vec{r}_{l+k}) - \vec{r}_j)$$

- The resulting Fourier coefficients then reconstruct the time dependence of electron impact source functions.

$$S_{ml}(t) = [e]_l N_{ml} \sum_{n=0}^{n_m} |k_{nml}| \sin(n\omega t + \phi_{nml}),$$

$$\phi_{nml} = \tan^{-1} \frac{\text{Im}(k_{nml})}{\text{Re}(k_{nml})}$$

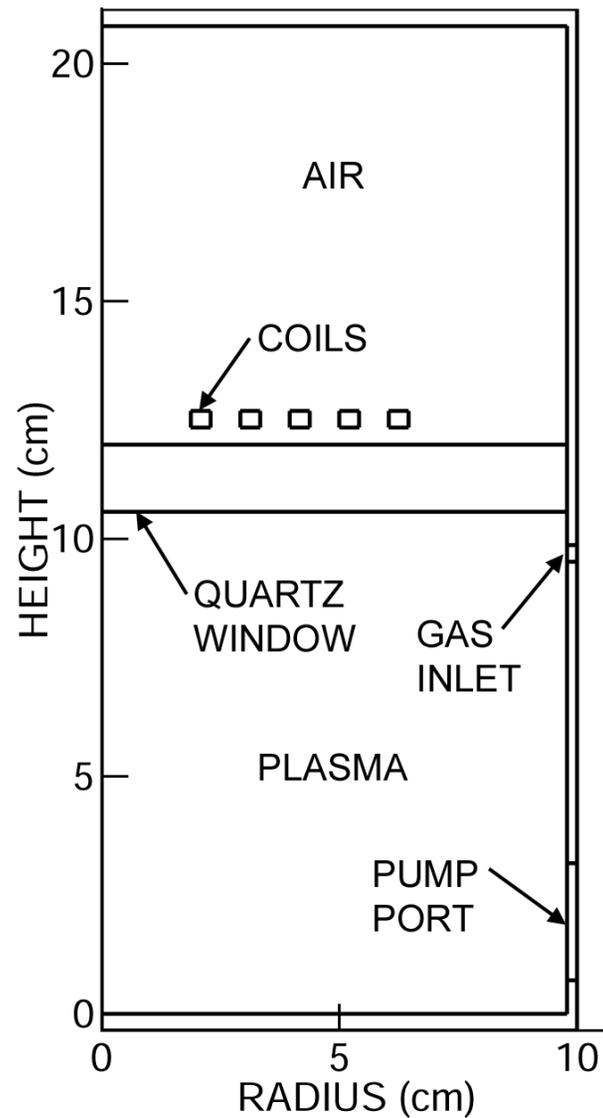
ALGORITHM FOR E-E COLLISIONS

- The basis of the algorithm for e-e collisions is “particle-mesh”.
- Statistics on the EEDs are collected according to spatial location.
- A collision target is randomly selected from the EED at that location and a random direction is assigned for the target’s velocity.
- The relative speed between the electron and its target electron is used to determine the probability for an e-e collision

$$P_{ee} = n_e(\vec{r}) \cdot \sigma_{ee}(v) \cdot v \cdot \Delta t, \quad v = |\vec{v}_{e1} - \vec{v}_{e2}|$$
$$\sigma_{ee}(v) = 4\pi b_o^2 \left[1 + \ln\left(\frac{\lambda_D}{b_o}\right) \right], \quad b_o = \frac{q^2 / 4\pi\epsilon_o}{\frac{1}{2}m_e v^2}$$

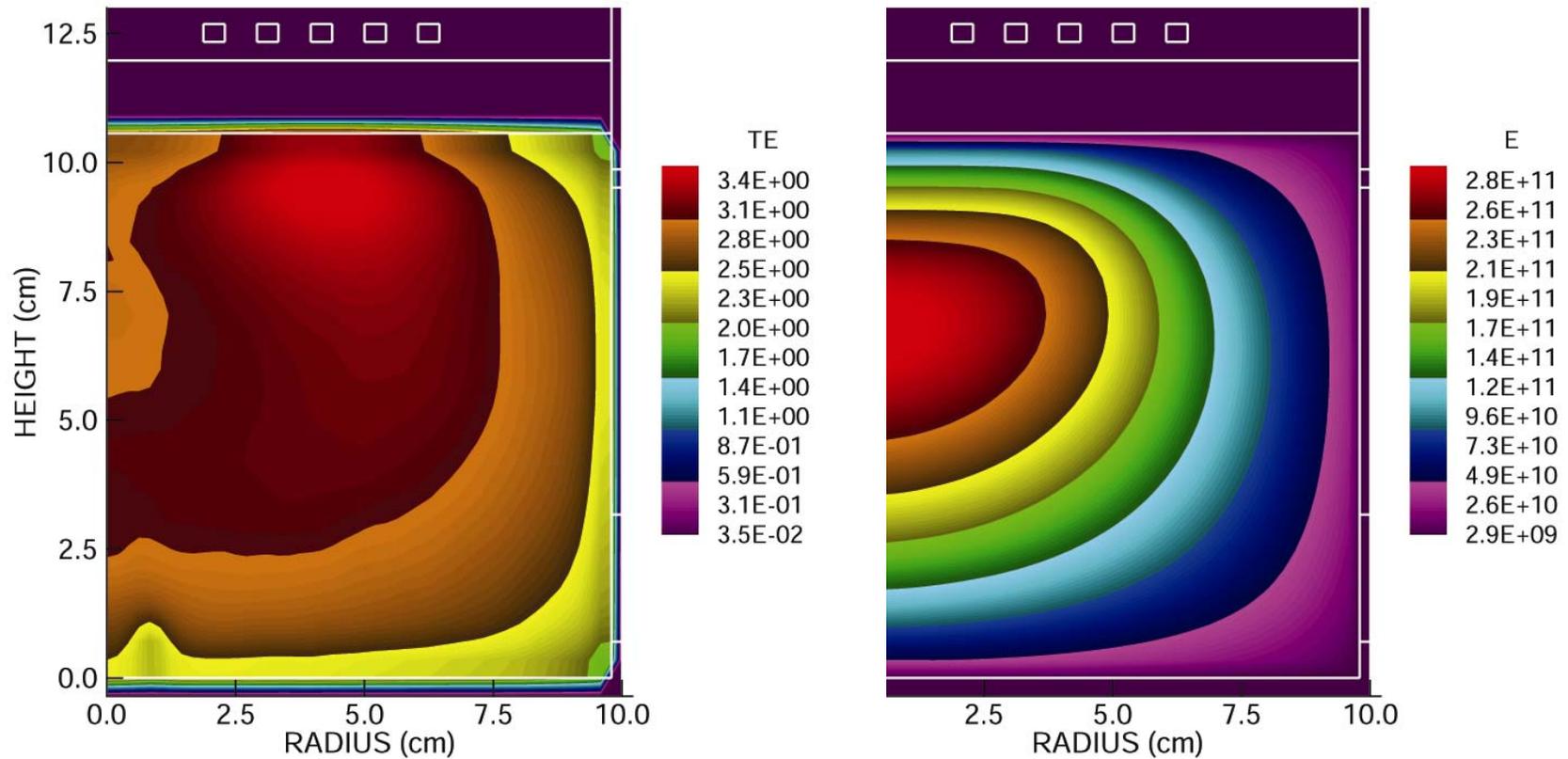
- If a collision occurs, classical collision dynamics determine the change in momentum of the electron.
- The consequences of e-e collisions on the targets are obtained by continuously updating the stored EEDs.

ICP CELL FOR INVESTIGATION



- The experimental cell is an ICP reactor with a Faraday shield to minimize capacitive coupling.

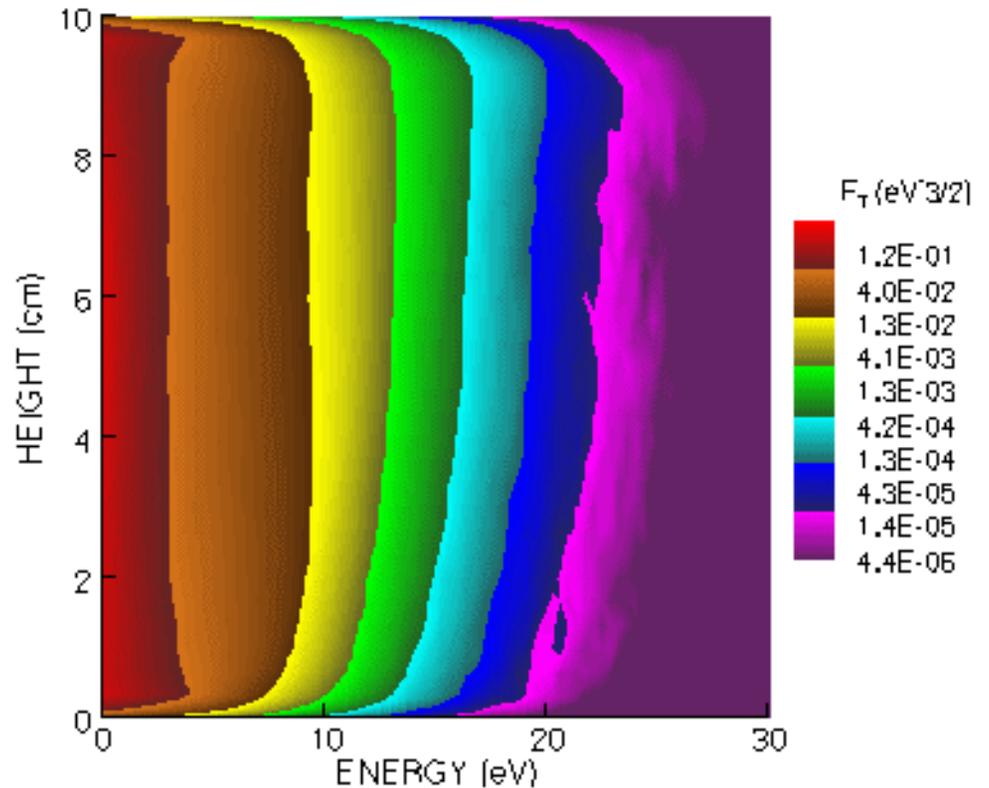
TYPICAL CONDITIONS: Ar, 10 mTorr, 200 W, 7 MHz



- On axis peak in [e] occurs in spite of off-axis power deposition and off-axis peak in electron temperature.

TIME DEPENDENCE OF THE EED

- Time variation of the EED is mostly at higher energies where electrons are more collisional.
- Dynamics are dominantly in the electromagnetic skin depth where both collisional and non-linear Lorentz Forces) peak.
- The second harmonic dominates these dynamics.



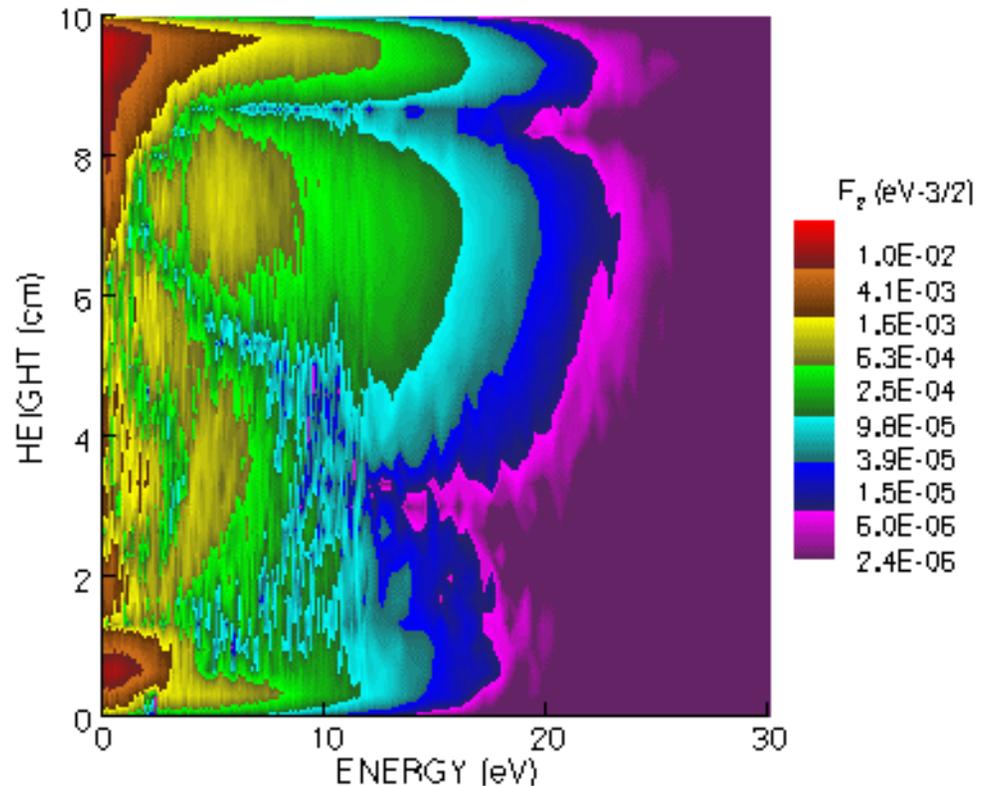
- Ar, 10 mTorr, 100 W, 7 MHz, $r = 4$ cm

ANIMATION SLIDE

University of Illinois
Optical and Discharge Physics

TIME DEPENDENCE OF THE EED: 2nd HARMONIC

- Electrons in skin depth quickly increase in energy and are “launched” into the bulk plasma.
- Undergoing collisions while traversing the reactor, they degrade in energy.
- Those surviving “climb” the opposite sheath, exchanging kinetic for potential energy.
- Several “pulses” are in transit simultaneously.



- Amplitude of 2nd Harmonic

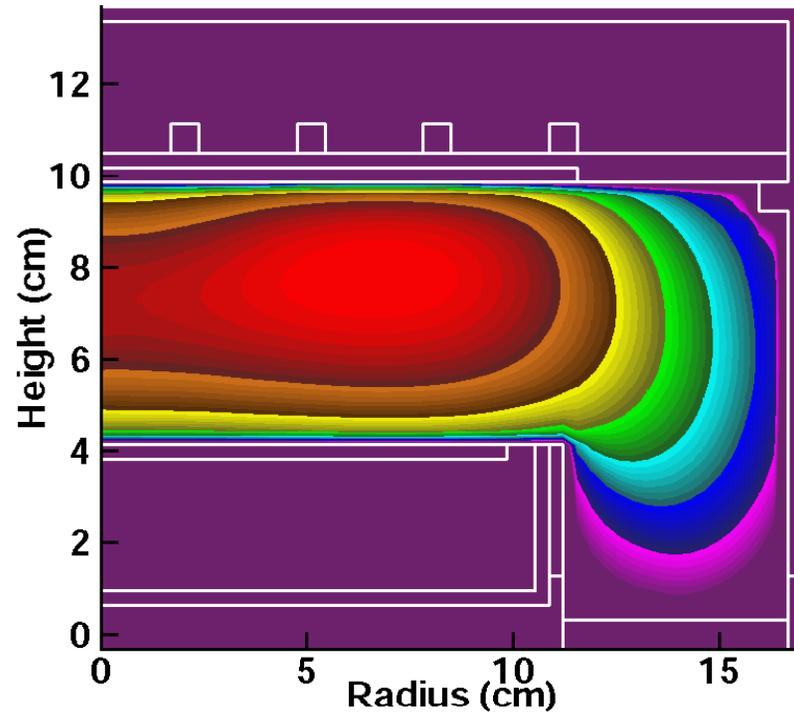
ANIMATION SLIDE

- Ar, 10 mTorr, 100 W, 7 MHz, $r = 4$ cm

University of Illinois
Optical and Discharge Physics

HARMONICS IN ICP

- To investigate harmonics an Ar/N₂ gas mixture was selected as having low and high threshold processes.
- $e^- + \text{Ar} \rightarrow \text{Ar}^+ + e^- + e^-$, $\Delta\varepsilon = 16 \text{ eV}$
High threshold reactions capture modulation in the tail of the EED.
- $e^- + \text{N}_2 \rightarrow \text{N}_2(\text{vib}) + e^-$, $\Delta\varepsilon = 0.29 \text{ eV}$
Low threshold reactions capture modulation of the bulk of the EED.
- **Base case conditions:**
 - Pressure: 5 mTorr
 - Frequency: 13.56 MHz
 - Ar / N₂: 90 / 10
 - Power : 650 W

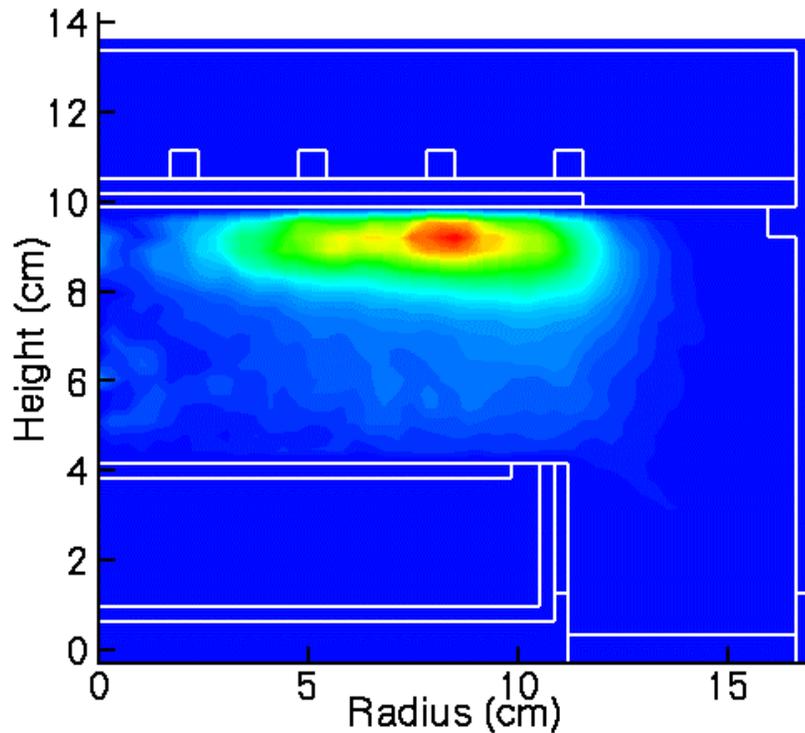


0.18  2.7

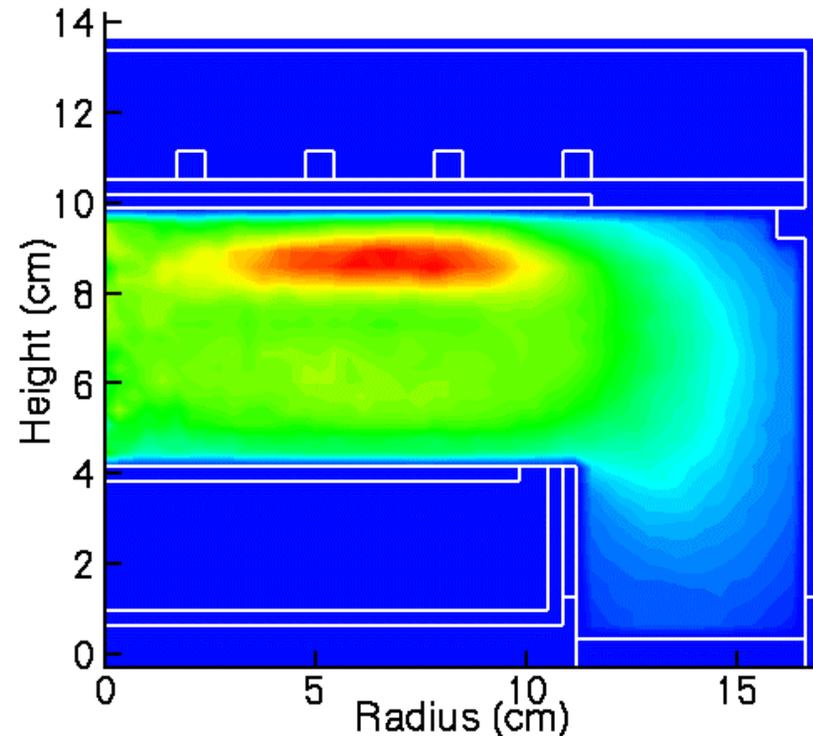
Electron density (10^{11} cm^{-3})

SOURCES FUNCTION vs TIME: THRESHOLD

- Ionization of Ar has more modulation than vibrational excitation of N₂ due to modulation of the tail of the EED.



- Ionization of Ar
 $6 \times 10^{14} - 3 \times 10^{16} \text{ cm}^{-3}\text{s}^{-1}$



- Excitation of N₂(v)
 $1.4 \times 10^{14} - 8 \times 10^{15} \text{ cm}^{-3}\text{s}^{-1}$

ANIMATION SLIDE

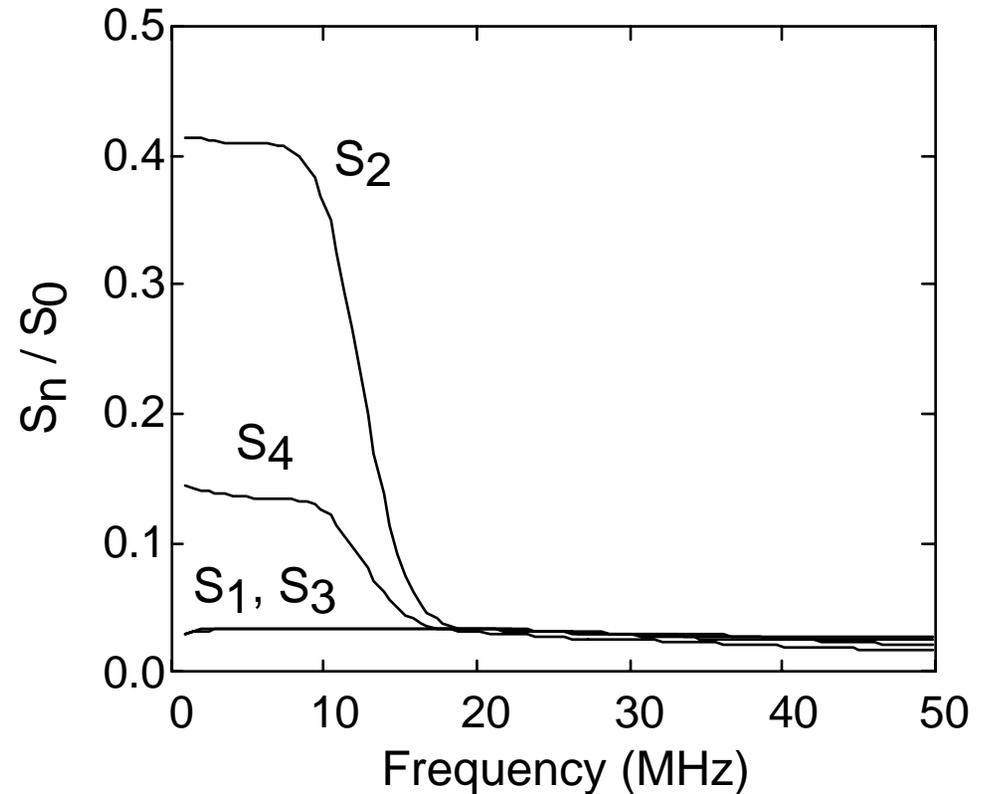
SNLA_0102_26

MIN  MAX

University of Illinois
Optical and Discharge Physics

HARMONICS OF Ar IONIZATION: FREQUENCY

- At large ω , both v_m/ω and $1/(v_m\omega)$ are small, and so both collisional and NLF harmonics are small.
- At small ω , both v_m/ω and $1/(v_m\omega)$ are large. Both collisional and NLF contribute to harmonics.



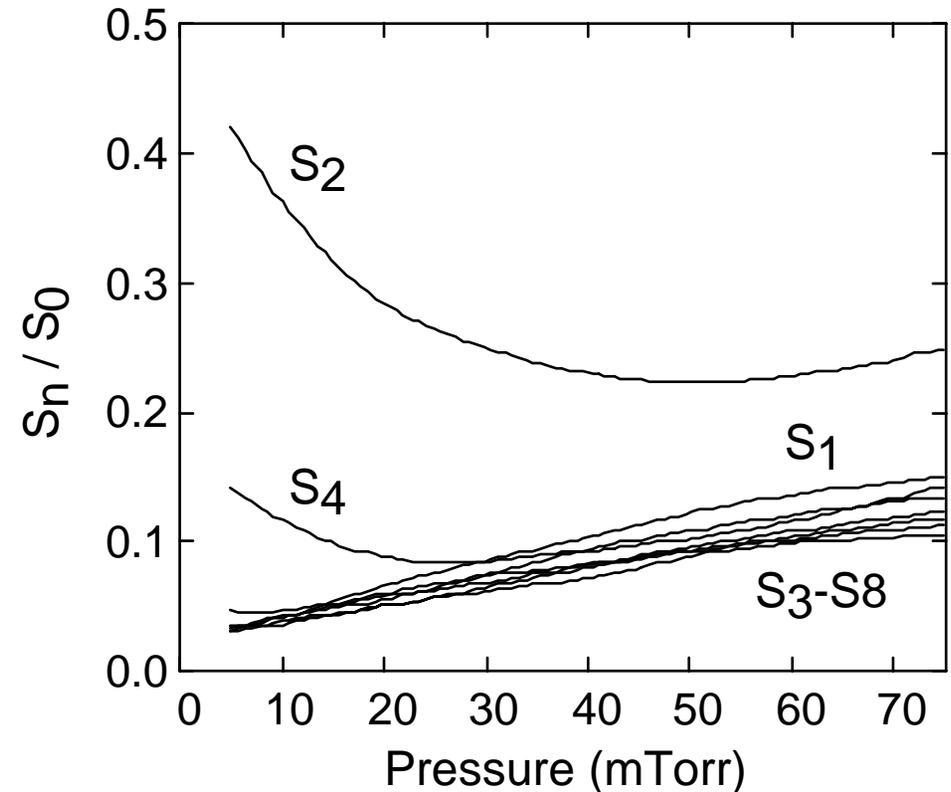
- Ar/N₂=90/10, 5 mTorr

- Harmonic Amplitude/Time Average

University of Illinois
Optical and Discharge Physics

HARMONICS OF Ar IONIZATION: PRESSURE

- At large P , v_m/ω is large and $1/(v_m\omega)$ is small. Harmonics result from collisional (or linear) processes.
- At small P , v_m/ω is small and $1/(v_m\omega)$ are large. Harmonics likely result from NLF.

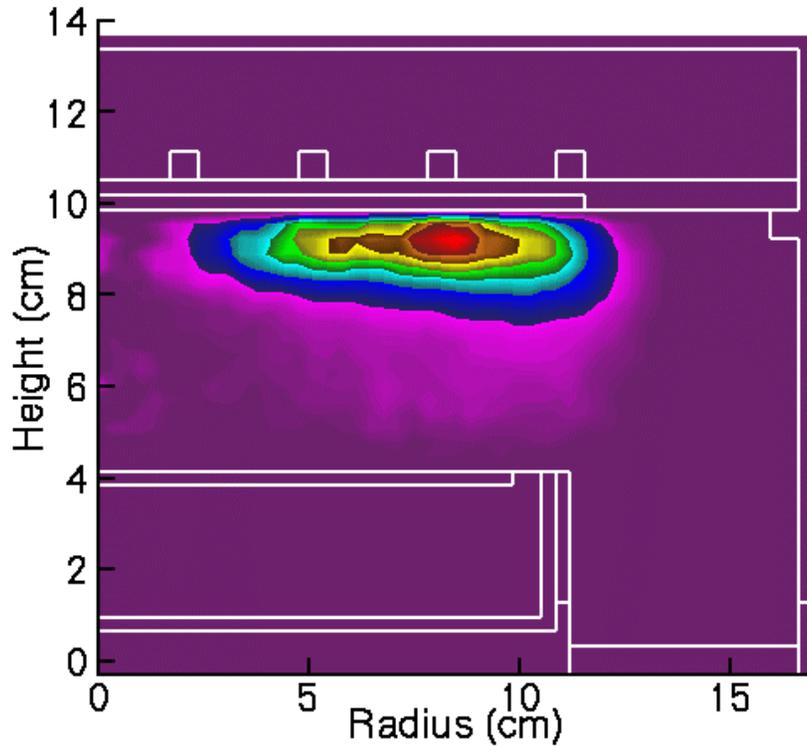


- Harmonic Amplitude/Time Average

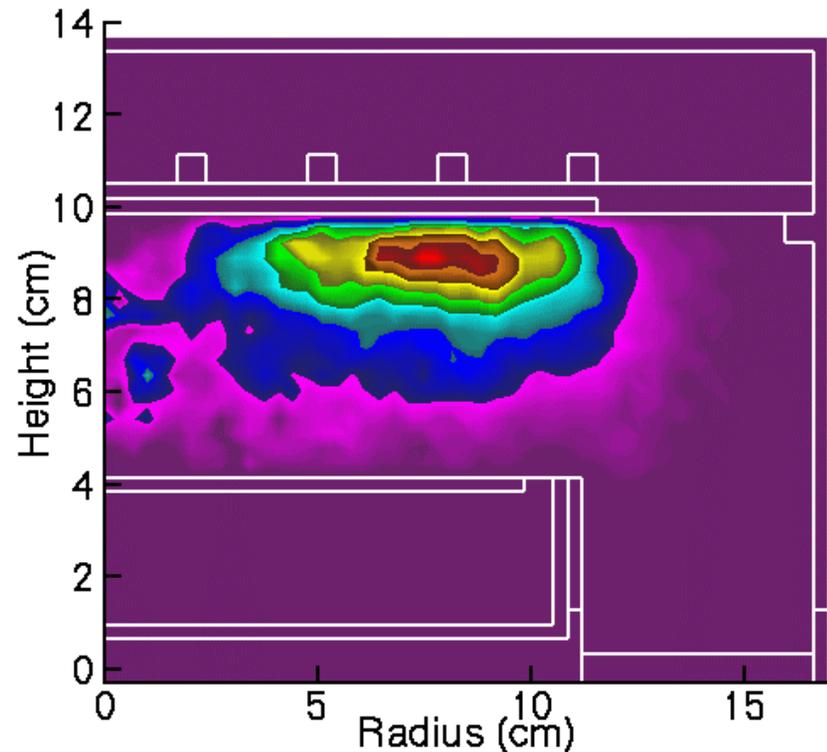
- Ar/N₂=90/10, 13.56 MHz

TIME DEPENDENCE OF Ar IONIZATION: PRESSURE

- Although B_{rf} may be nearly the same, at large P , v_0 and mean-free-paths are smaller, leading to lower harmonic amplitudes.



• 5 mTorr
 $6 \times 10^{14} - 3 \times 10^{16} \text{ cm}^{-3}\text{s}^{-1}$



• 20 mTorr
 $1.5 \times 10^{14} - 1.7 \times 10^{16} \text{ cm}^{-3}\text{s}^{-1}$

ANIMATION SLIDE

MIN  MAX